

1/39

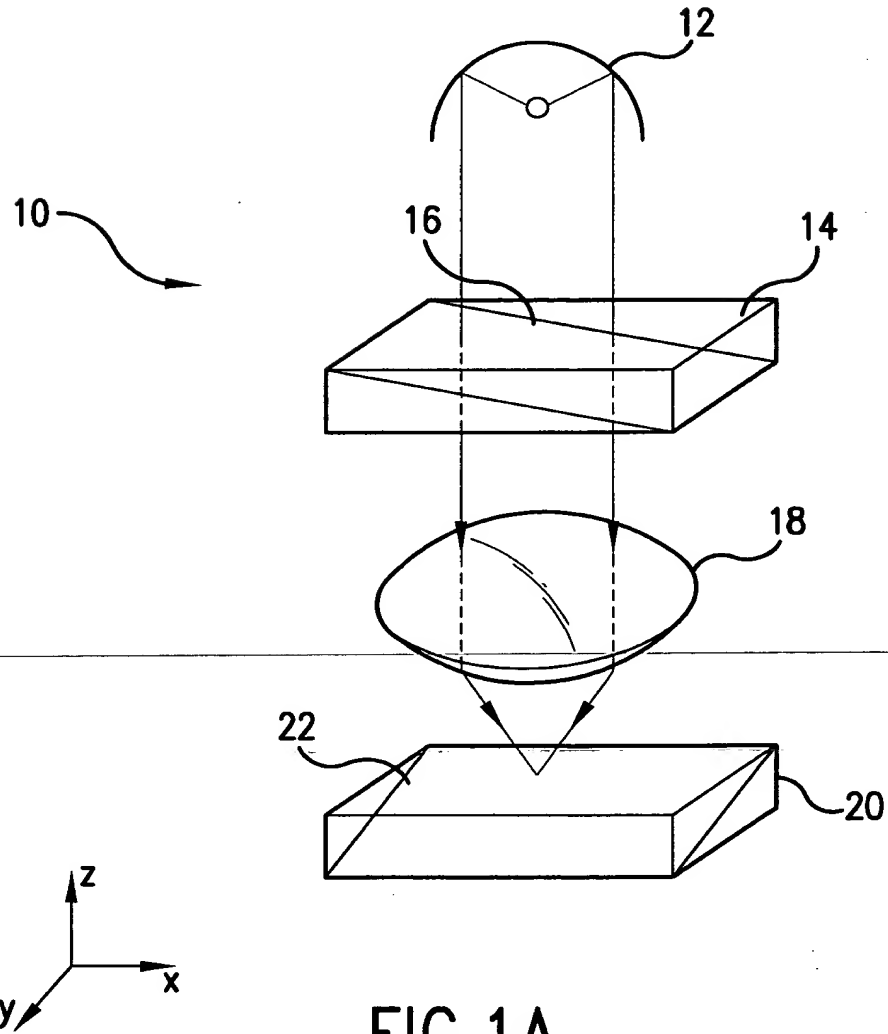


FIG. 1A

09907902.102901

2/39

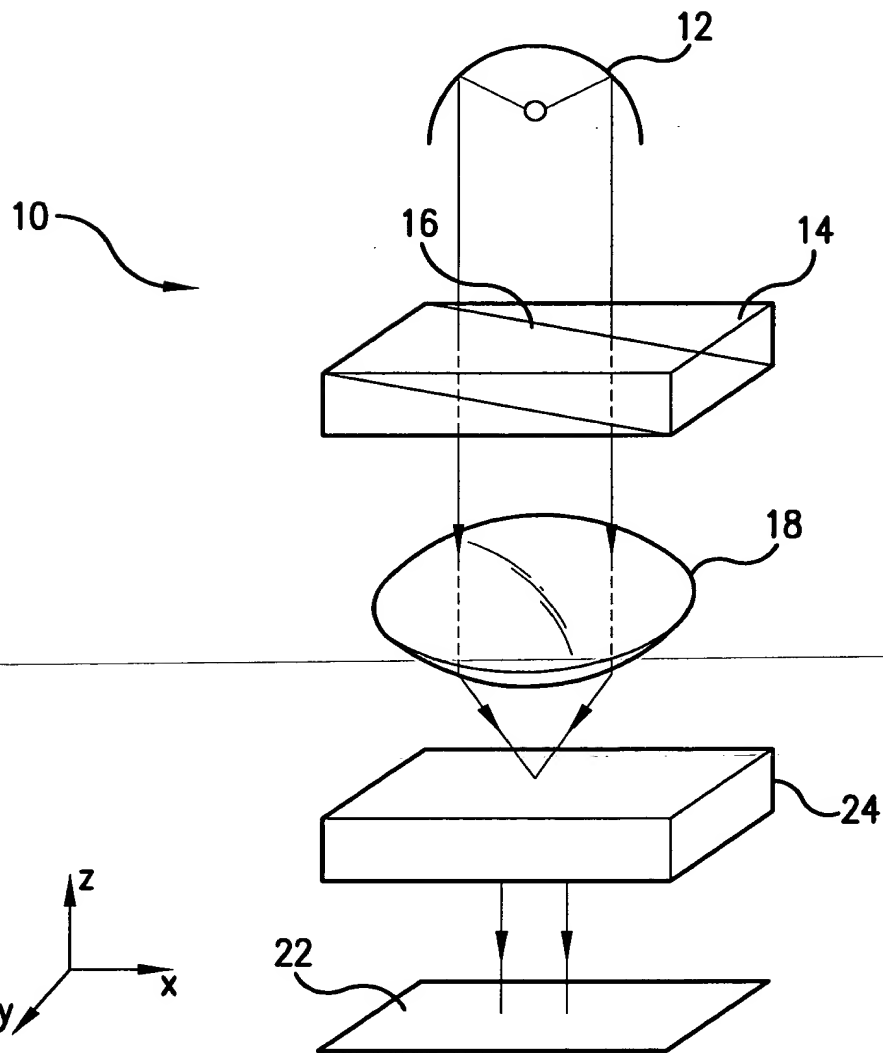


FIG. 1B

3/39

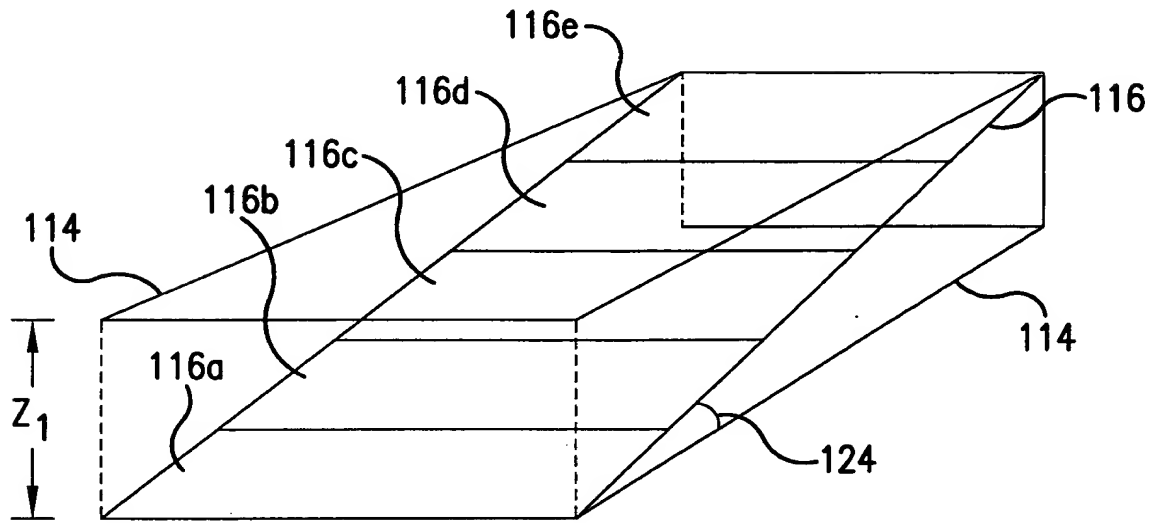


FIG. 2

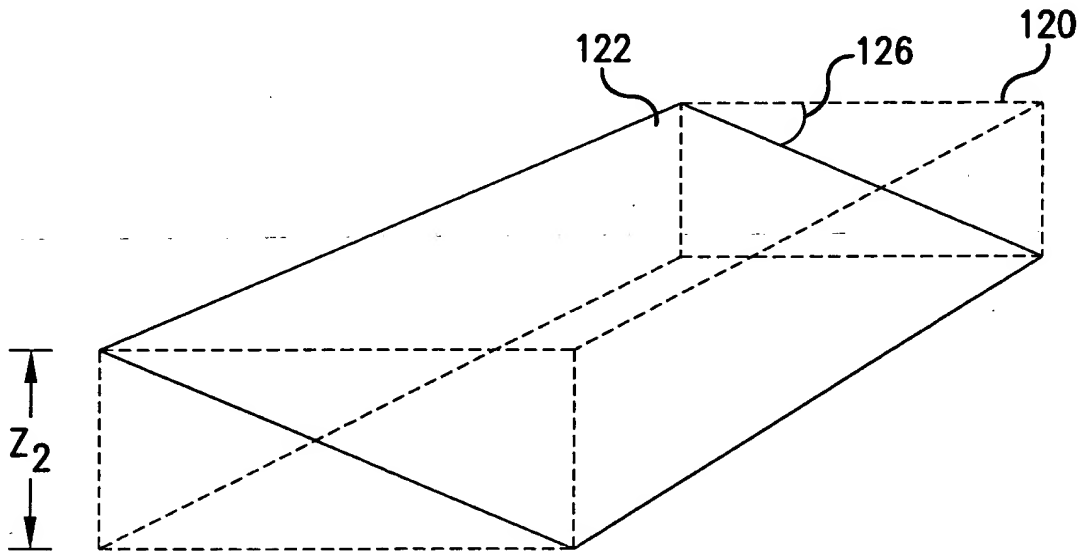
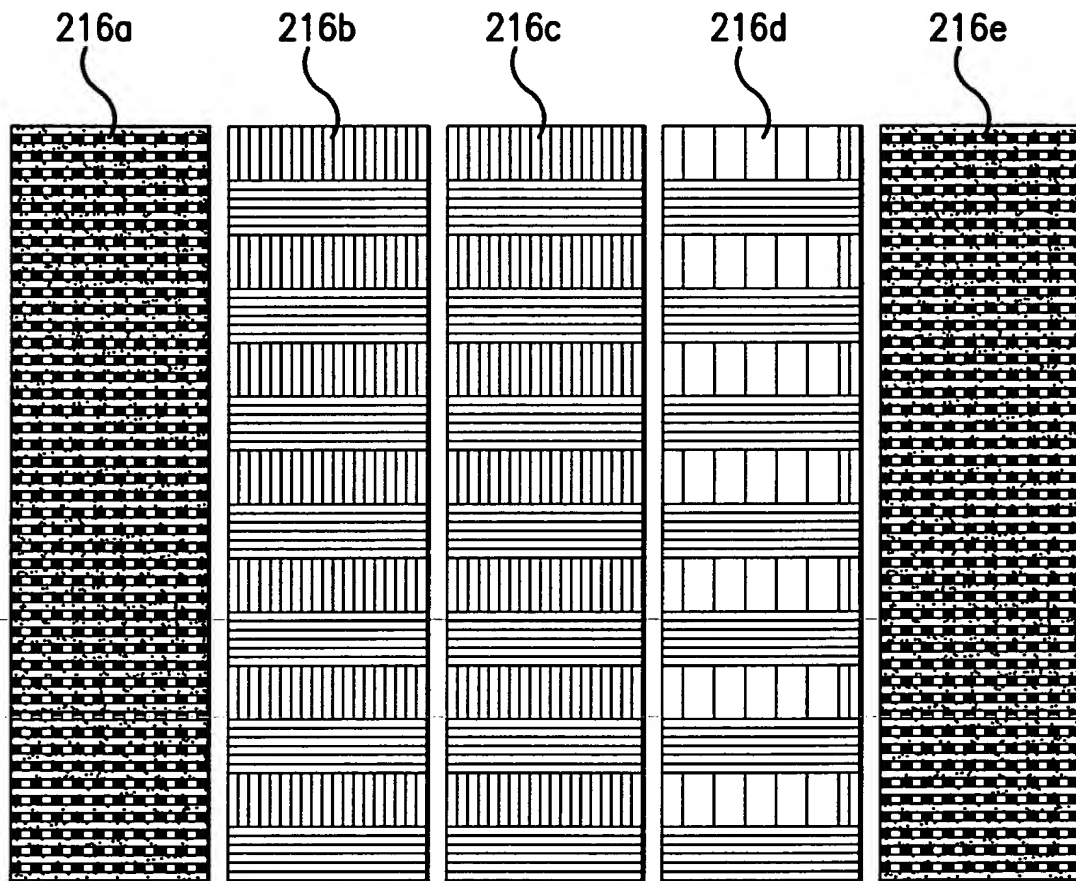


FIG. 3

FIG. 2 OF 20020650

4/39



216

FIG.4

FIG. 4 of 2002-06-06

5/39

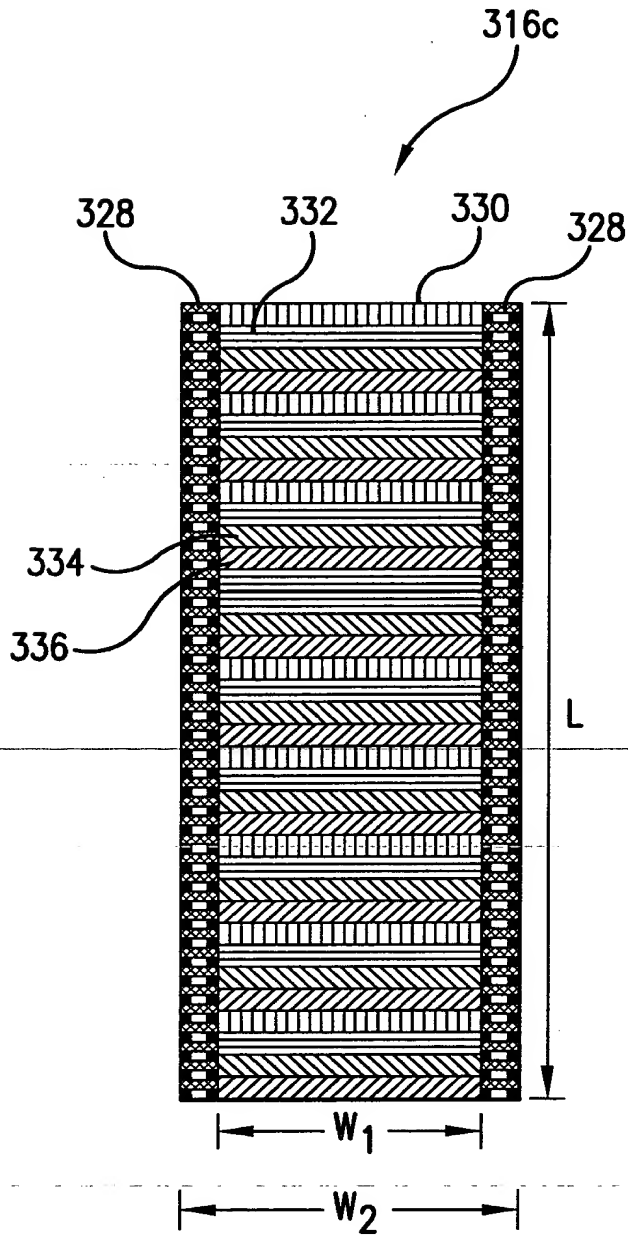


FIG.5A

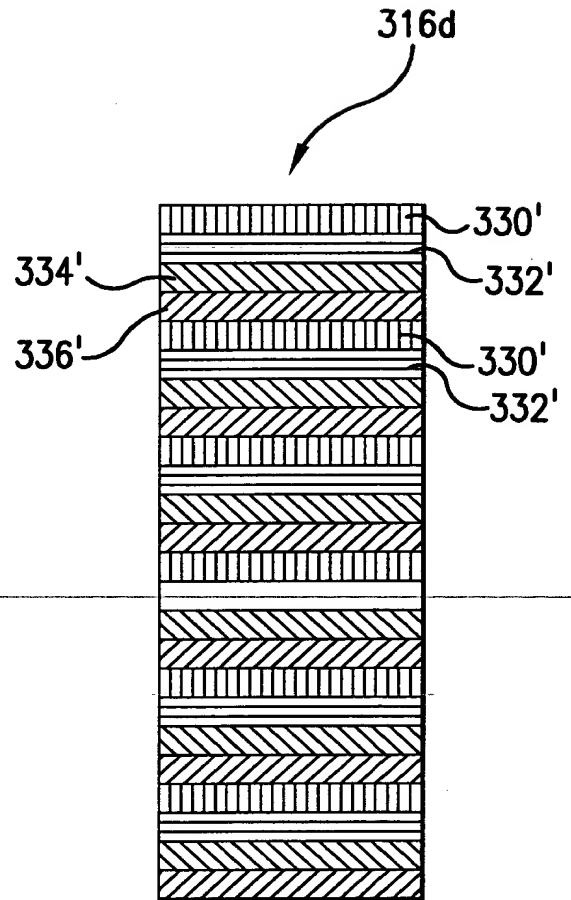


FIG.5B

6/39

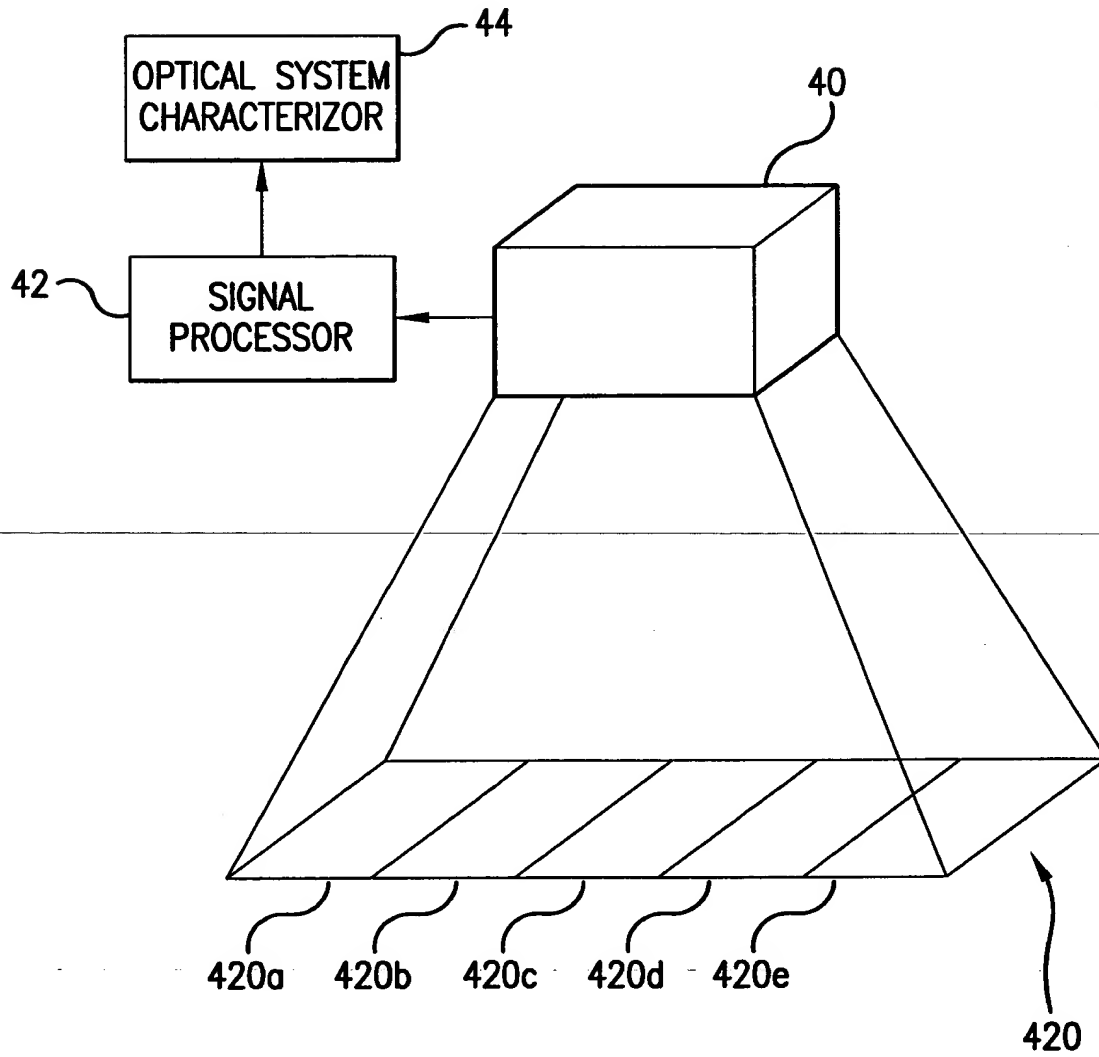


FIG. 6

7/39

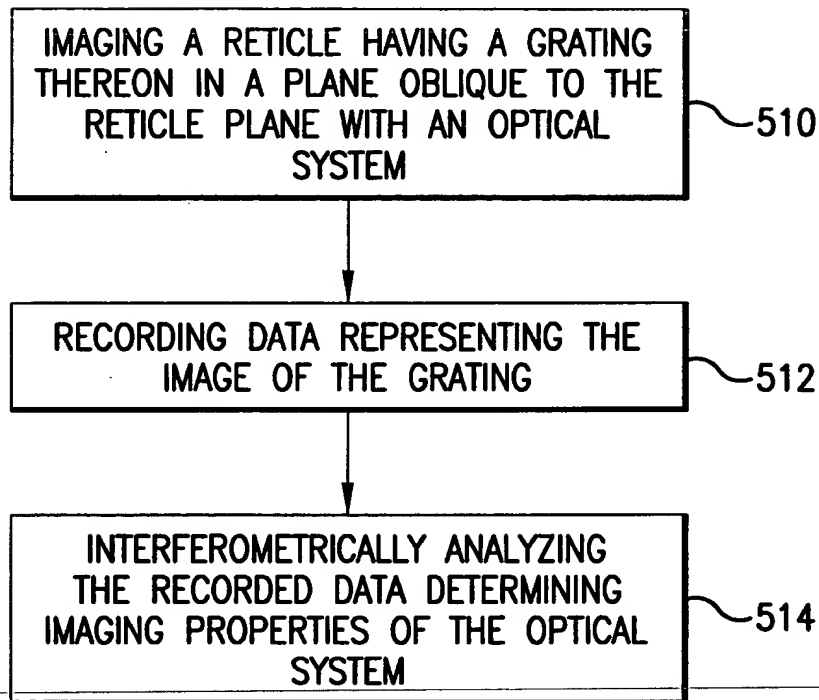


FIG. 7

105207-20640660

8/39

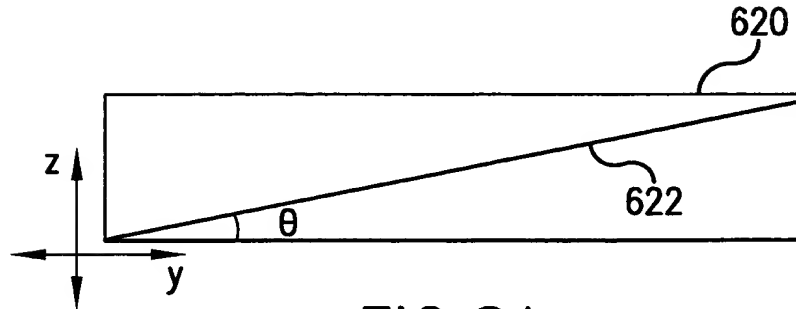


FIG. 8A

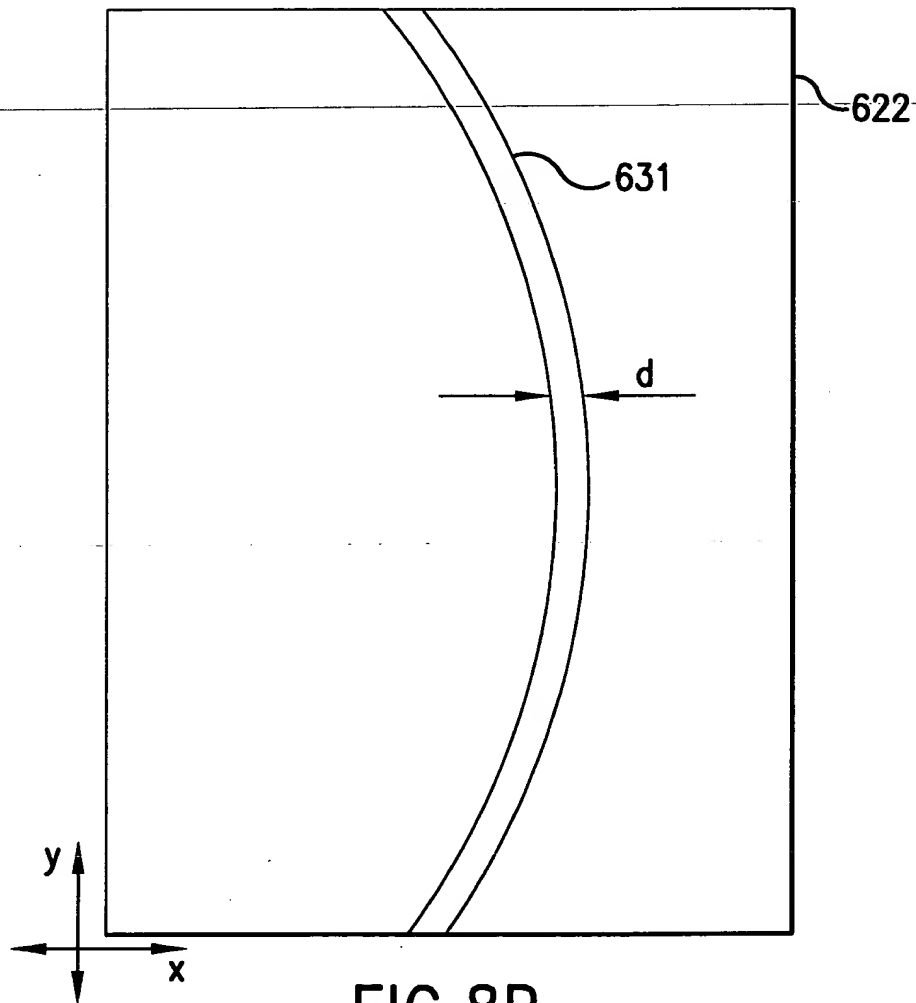
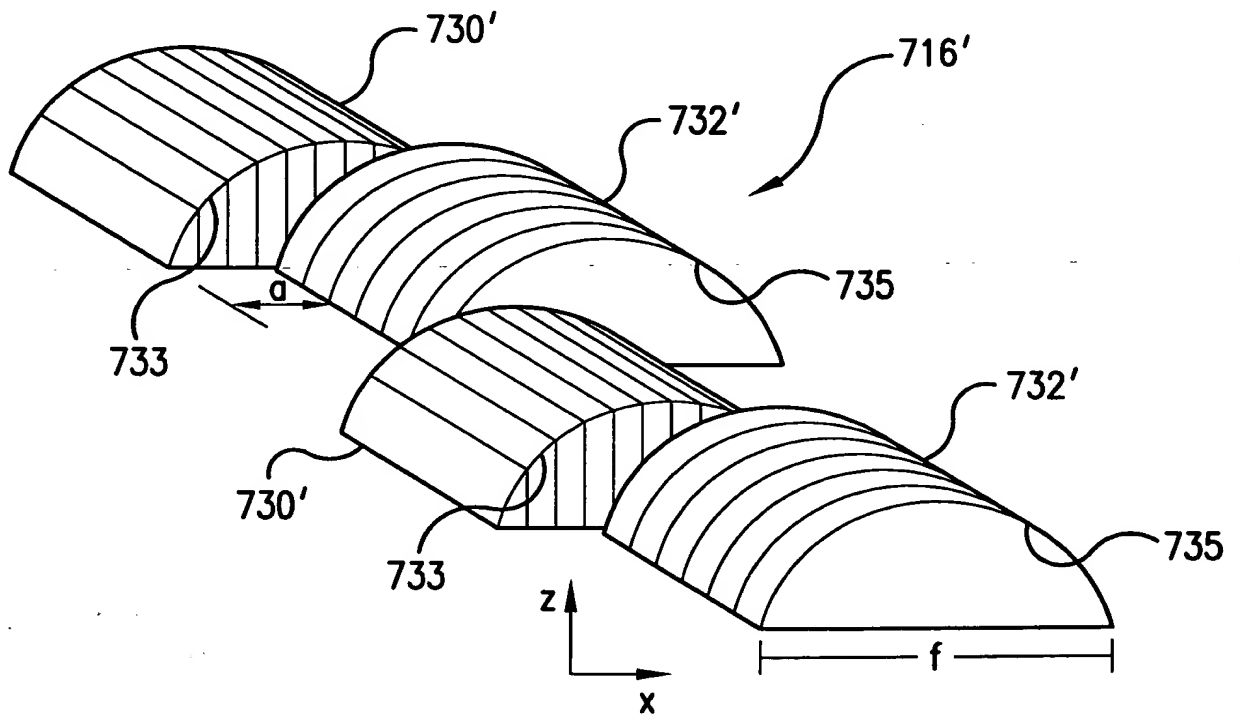
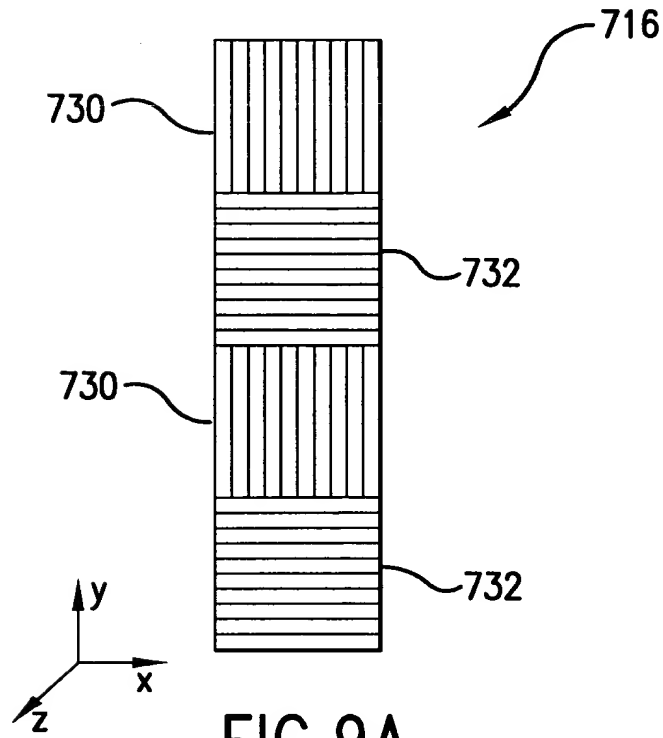


FIG. 8B

FIG. 8A



9/39



10/39

FIG. 10A

817

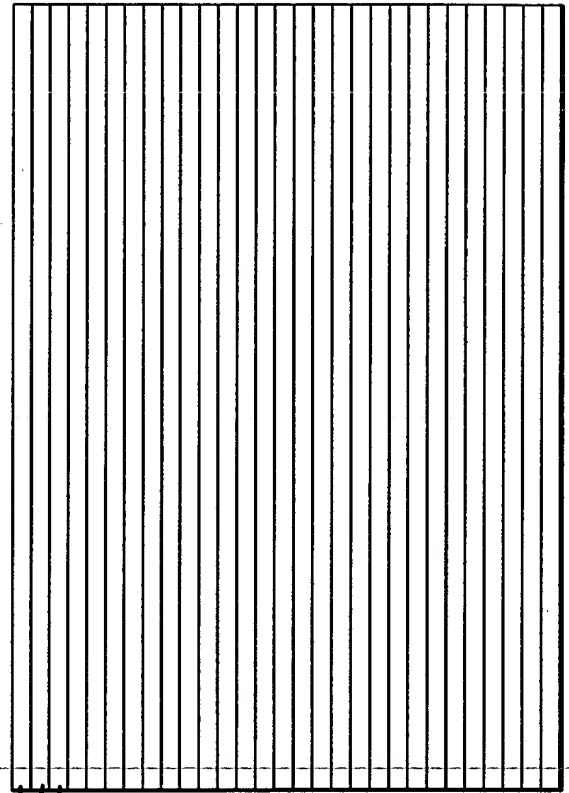
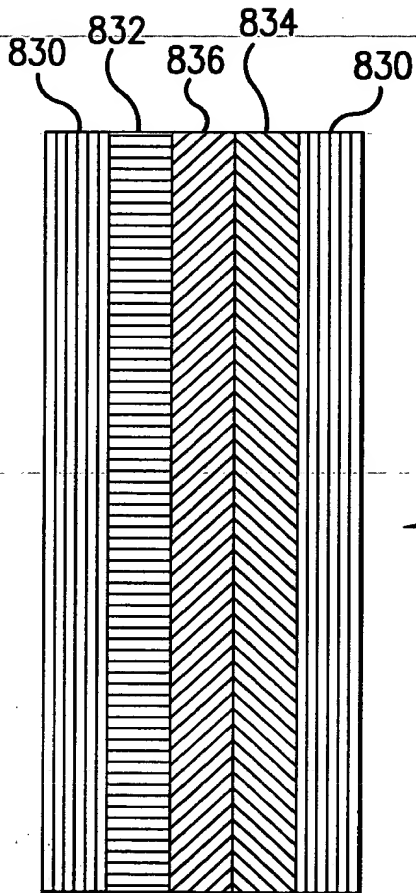


FIG. 10A

816



816

FIG. 10B

11/39

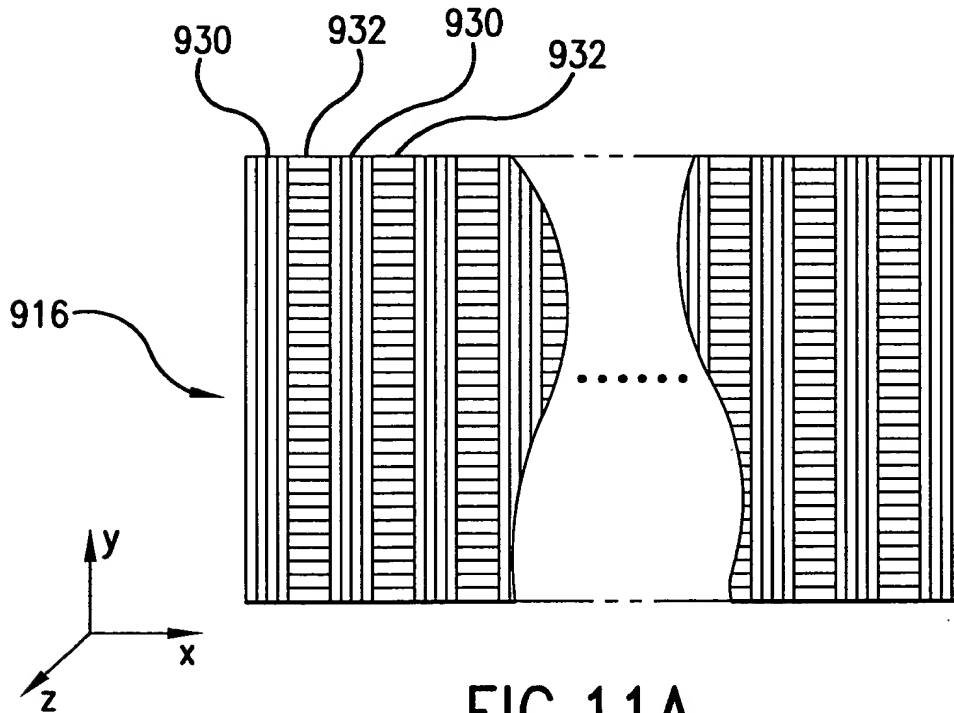


FIG. 11A

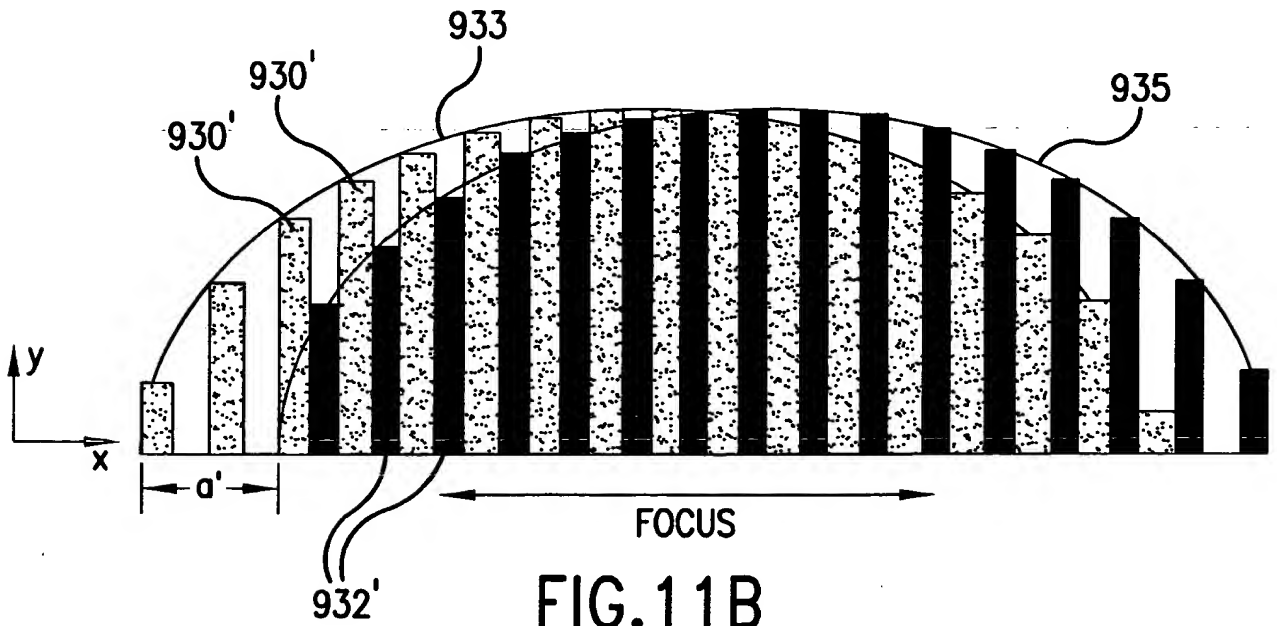


FIG. 11B

12/39

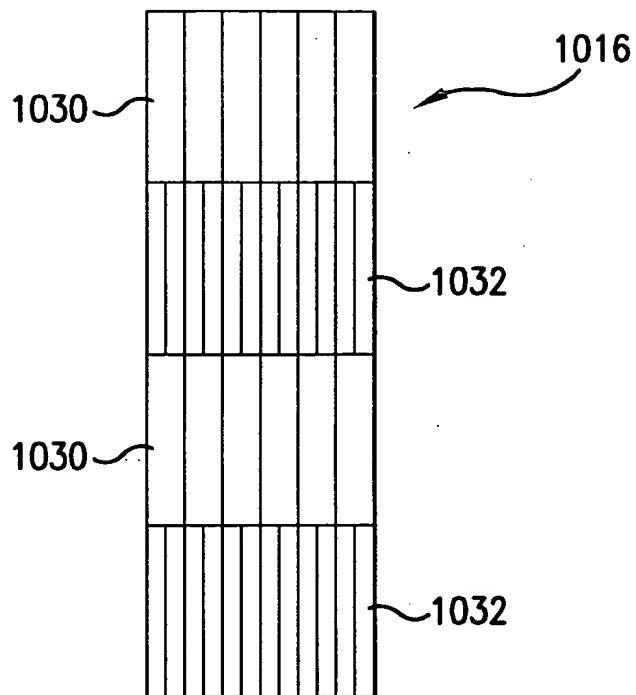


FIG.12

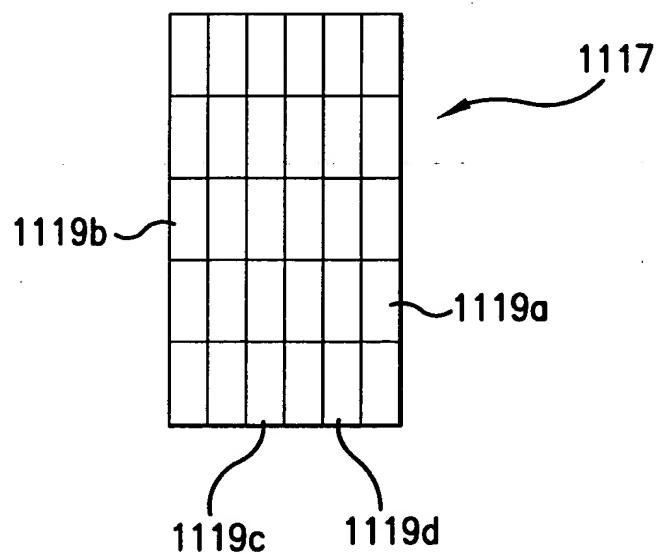


FIG.13

FOOT-2004-0550

13/39

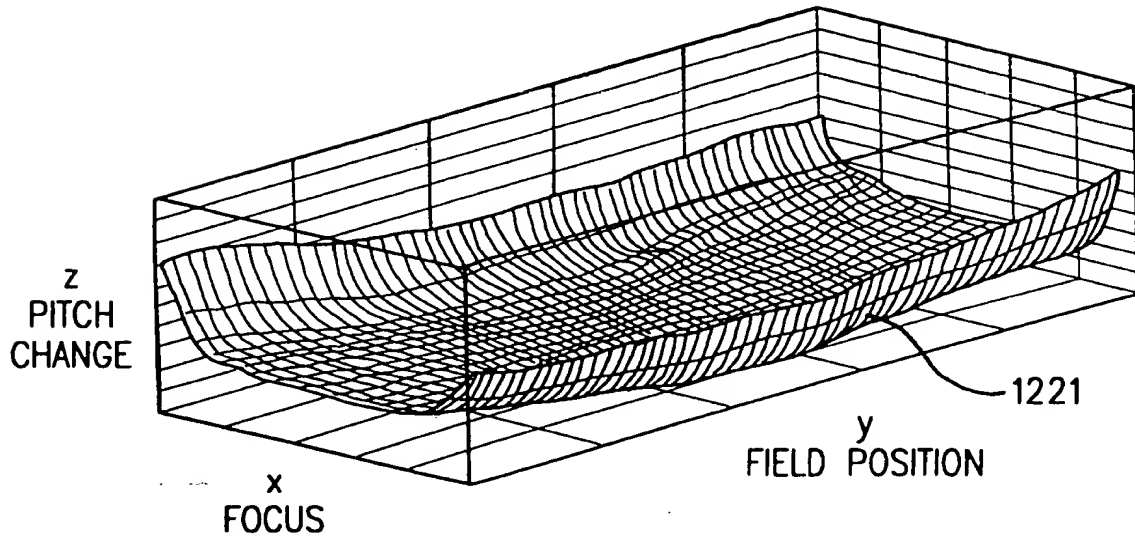


FIG. 14

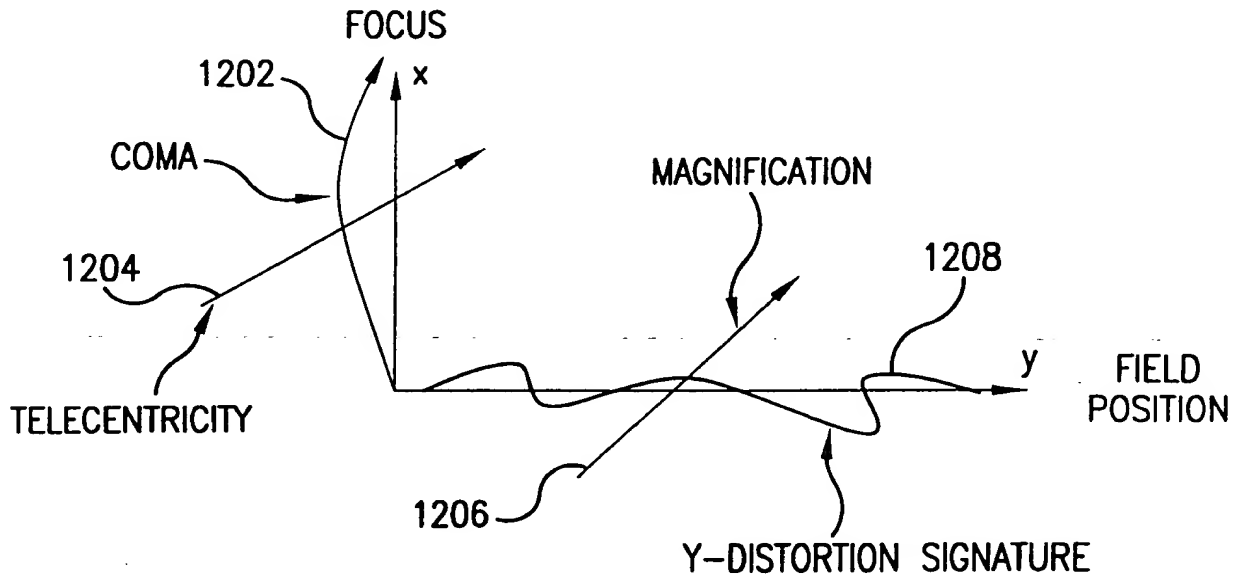
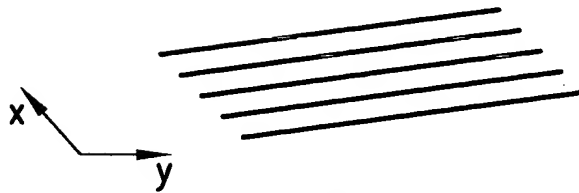


FIG. 15

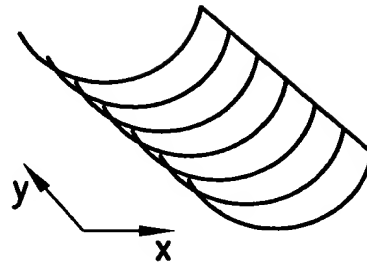
106201-20640660

14/39



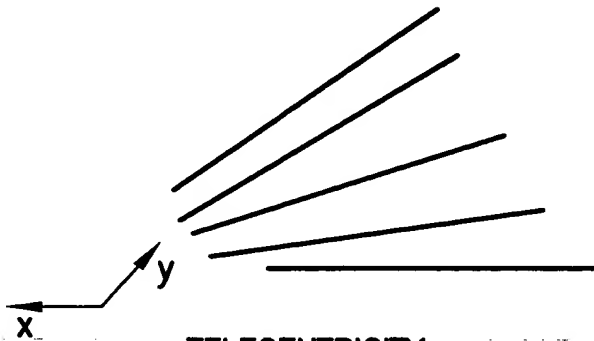
MAGNIFICATION

FIG.16A



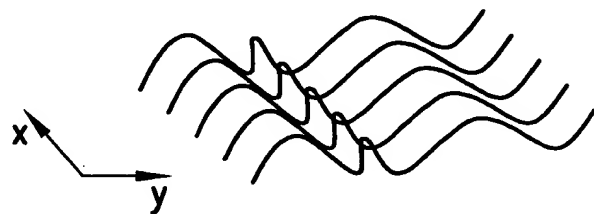
COMA

FIG.16B



TELECENTRICITY

FIG.16C



Y-DISTORTION SIGNATURE

FIG.16D

106201" 20640650

15/39

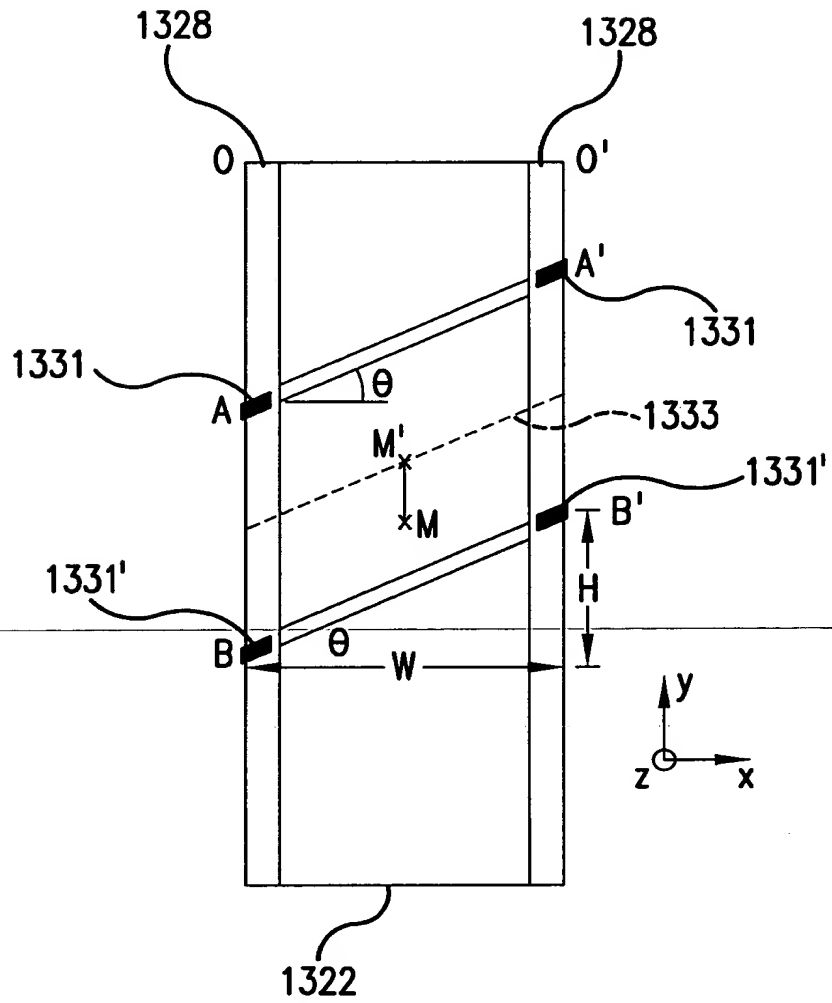


FIG.17

09907902.102901

16/39

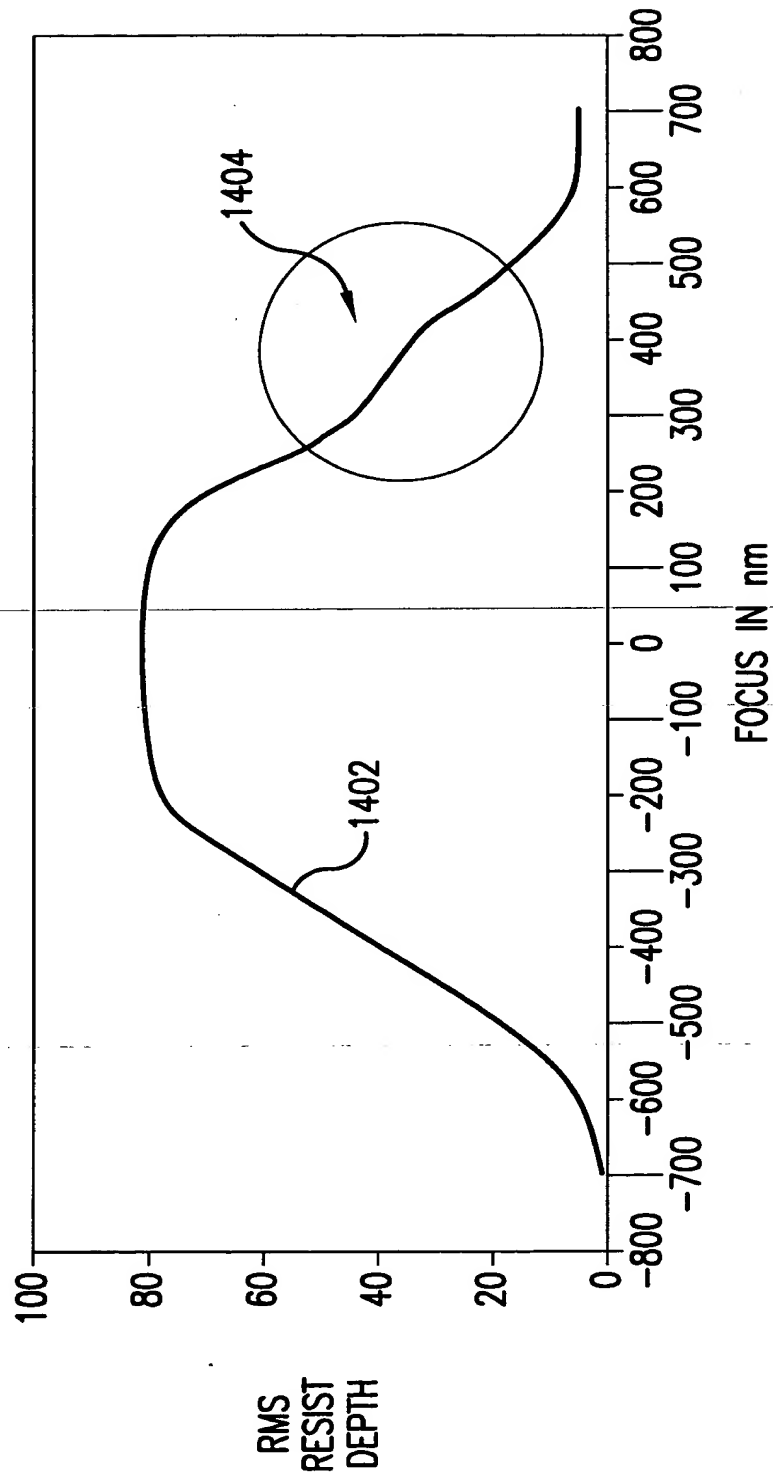


FIG. 18

FOCUS IN nm



17/39

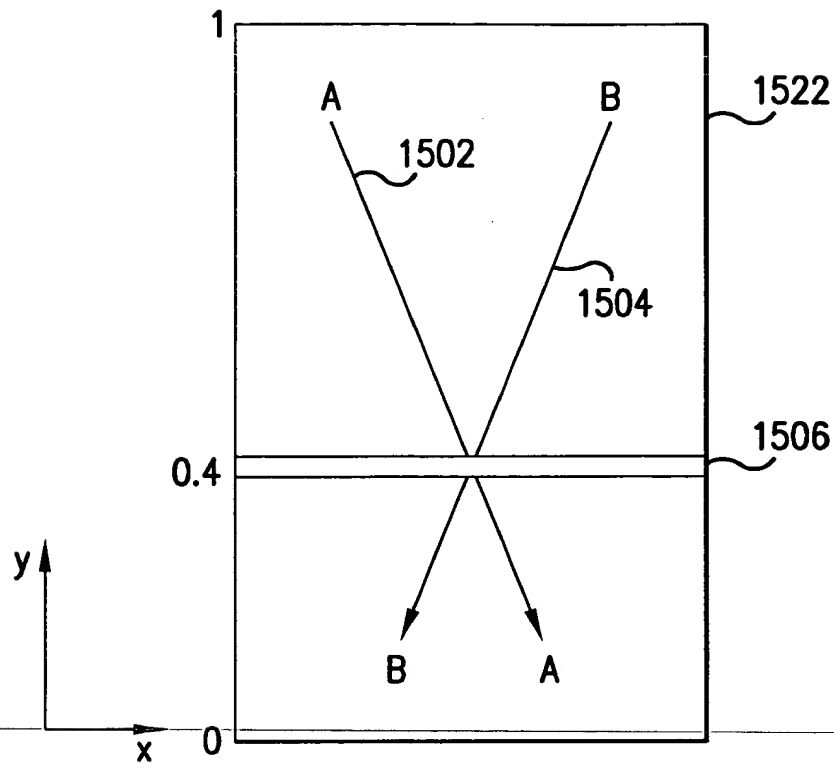


FIG.19A

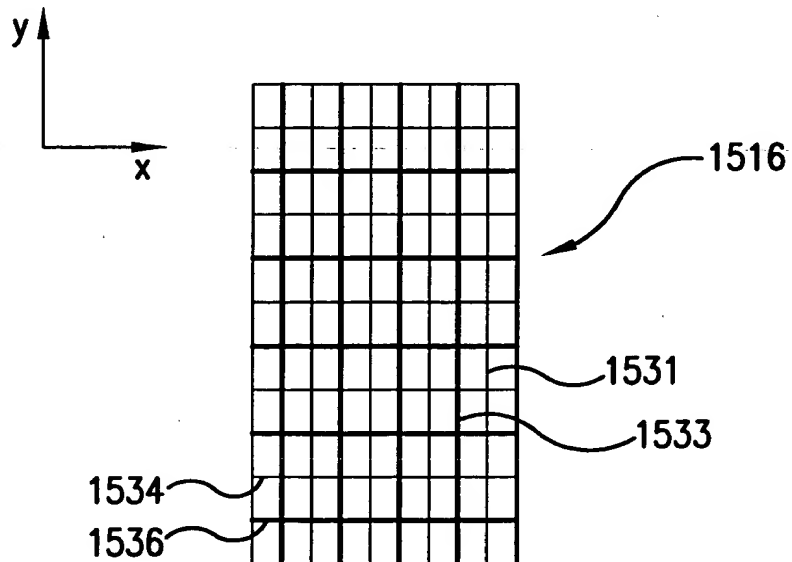


FIG.19B

18/39

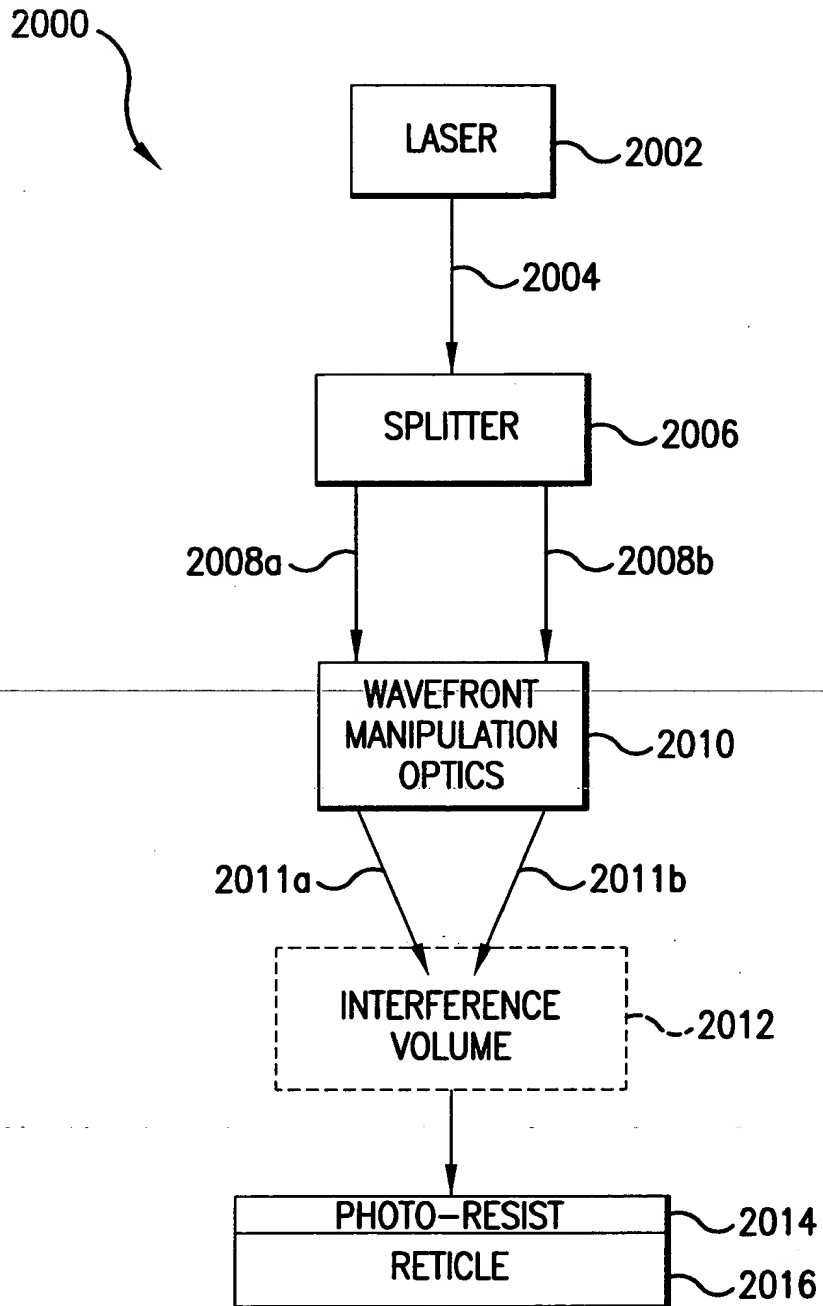


FIG.20

FOOT-20620660

19/39

2100

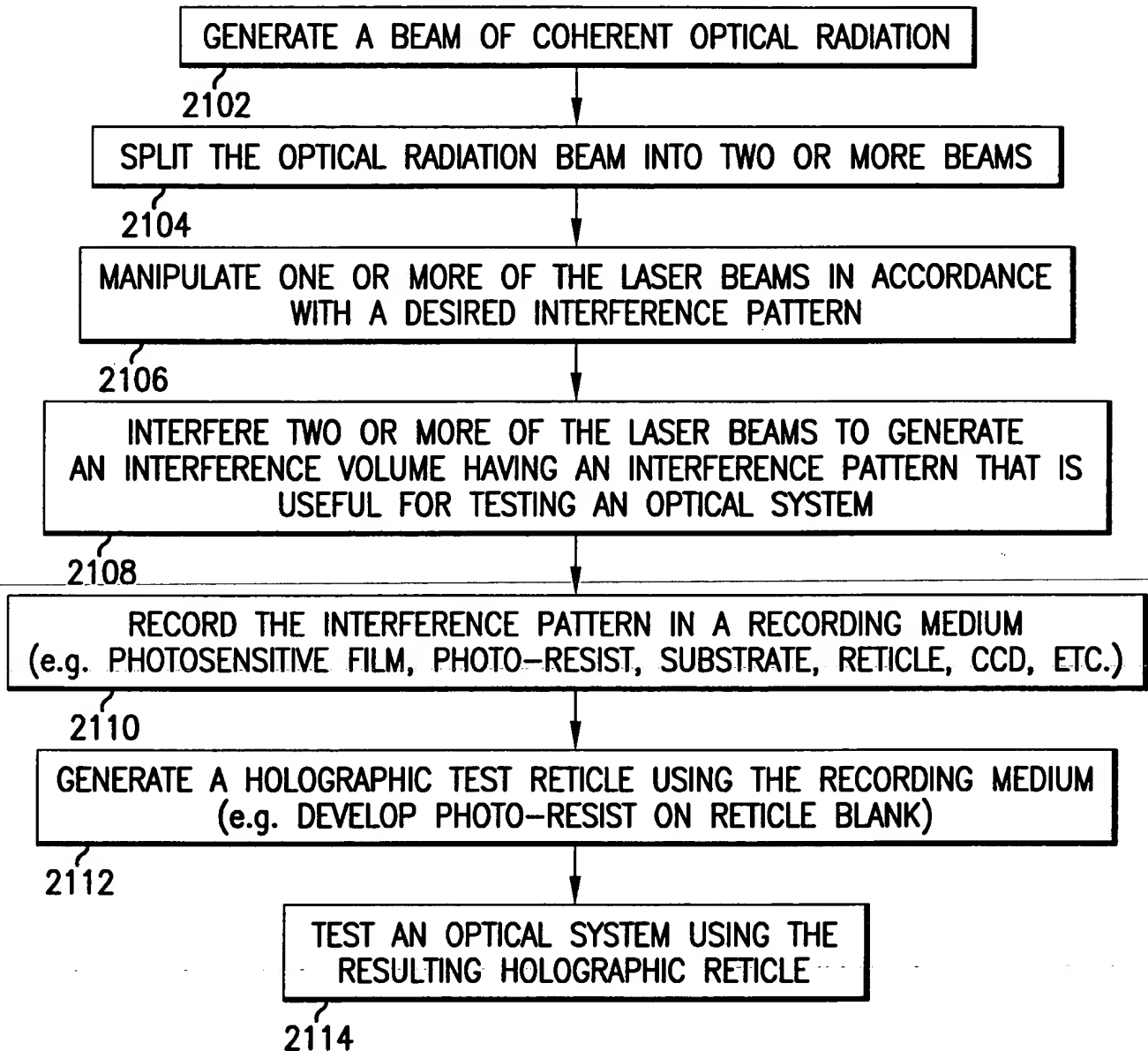


FIG.21

20/39

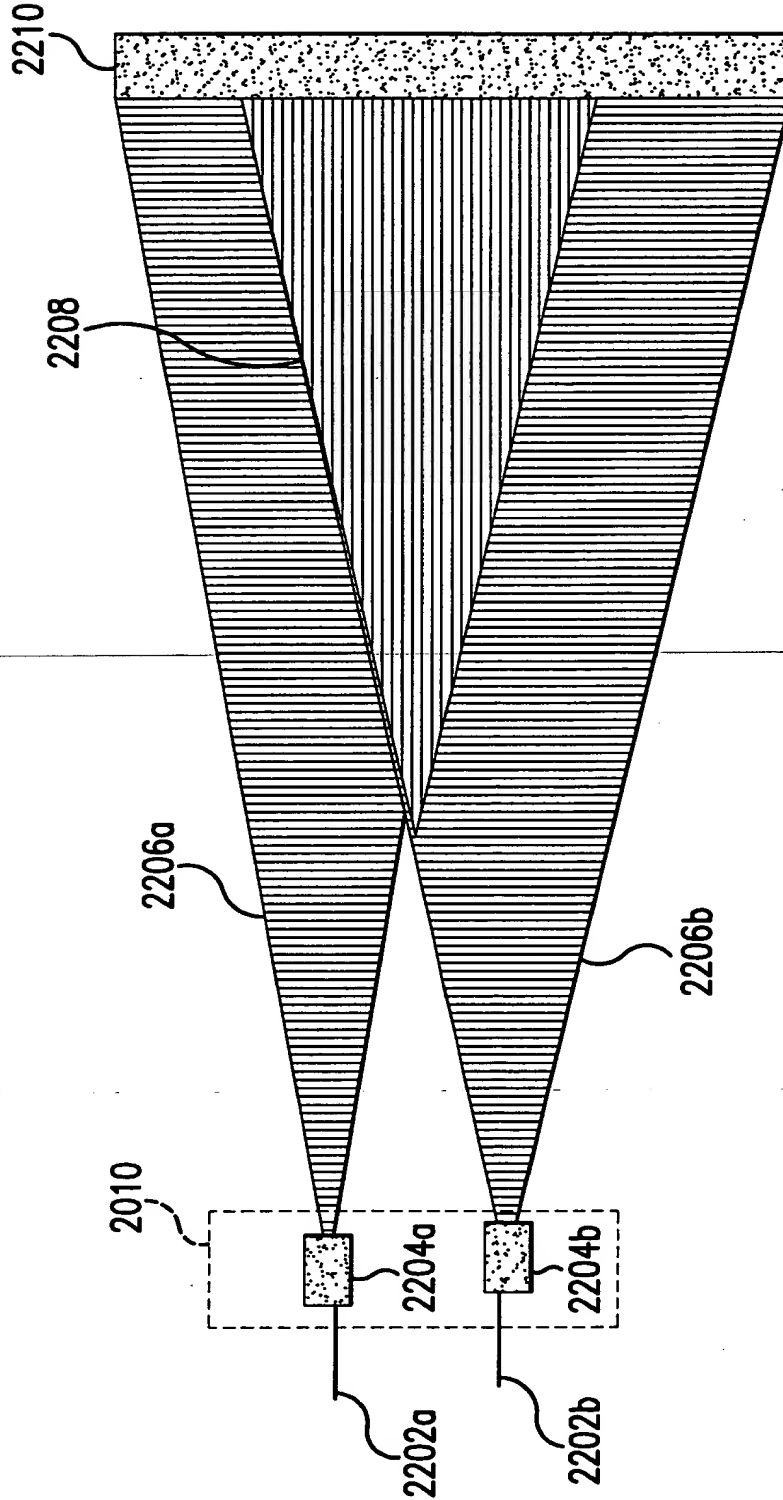


FIG. 22A

FIG. 22A

21/39

FOI 201-20620660

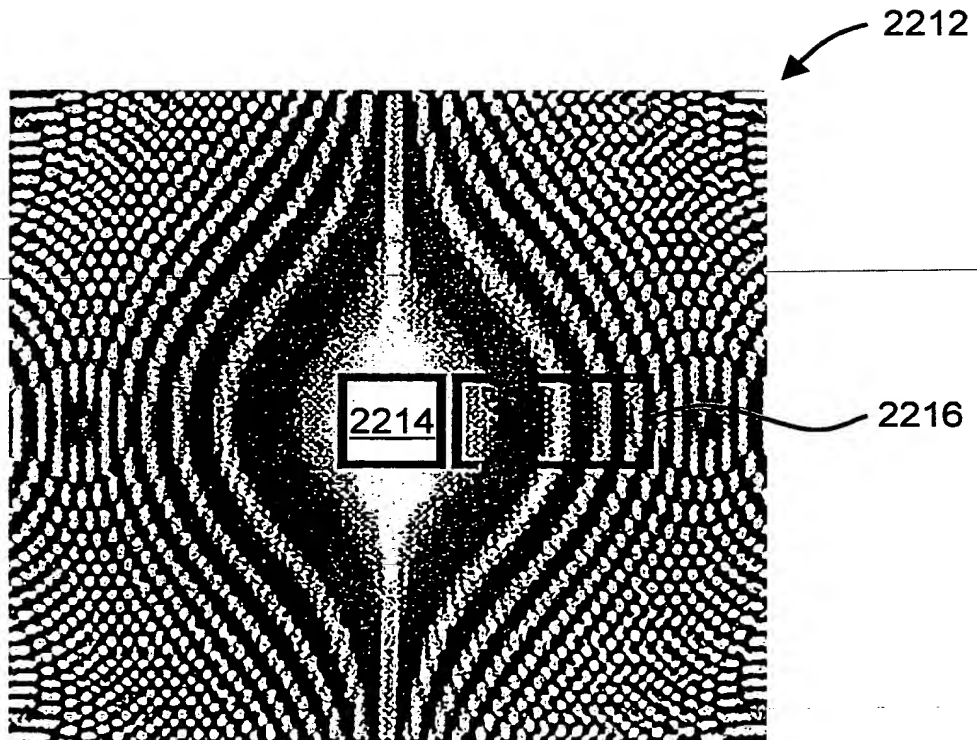
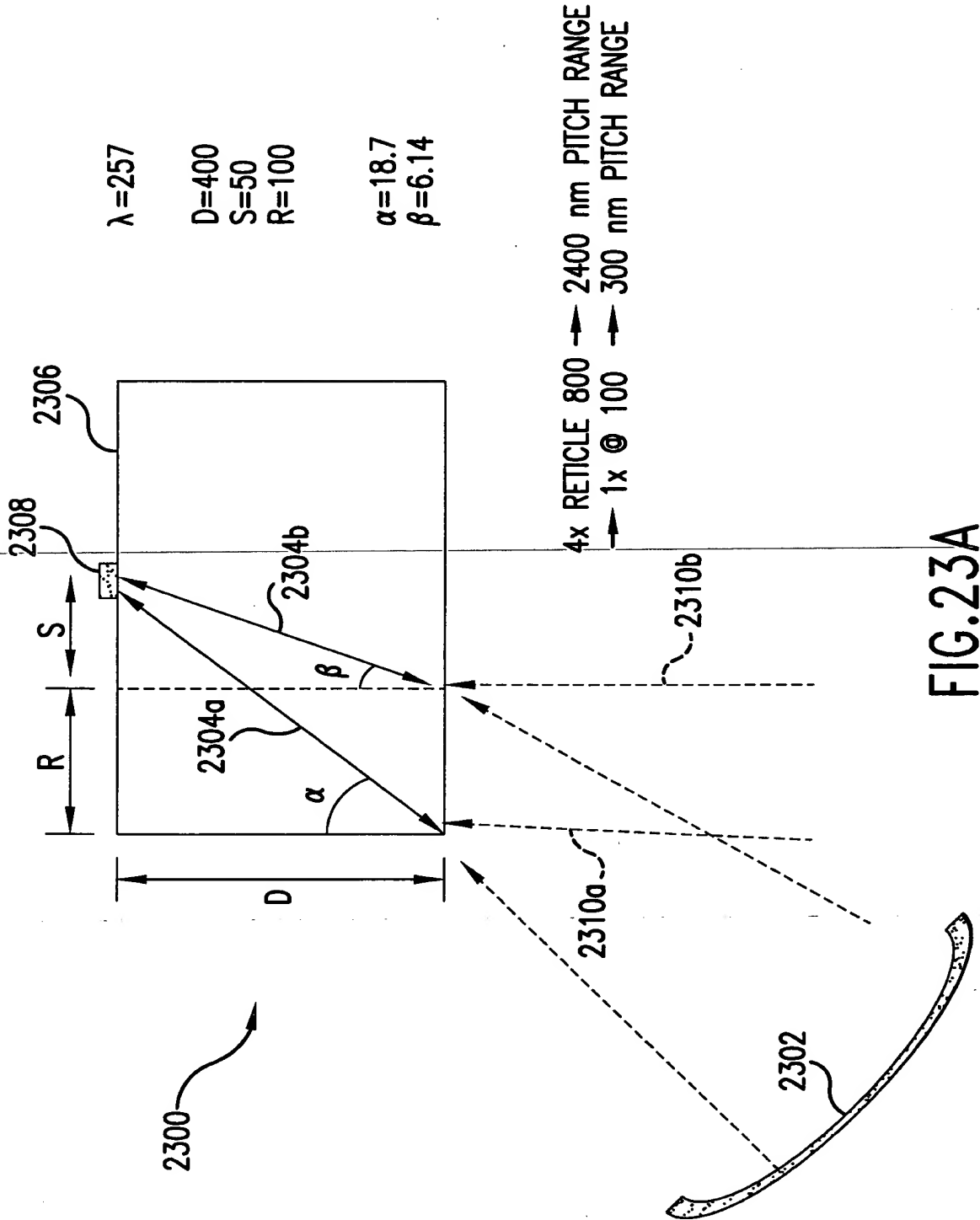
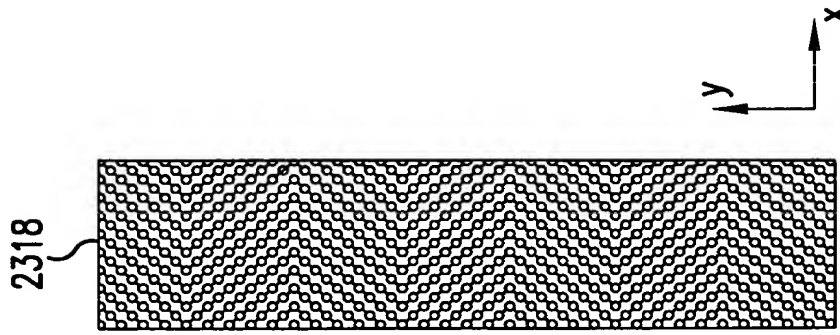


FIG.22B

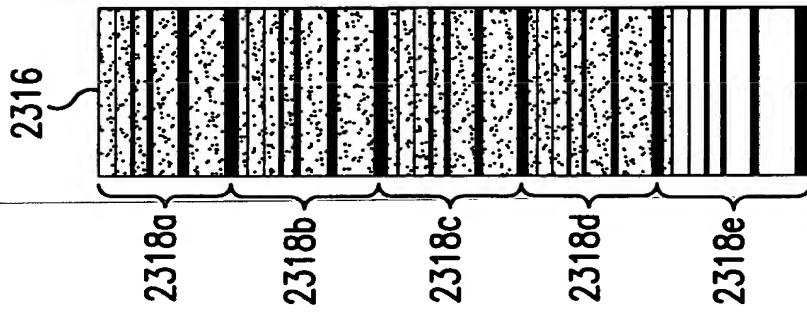
22/39



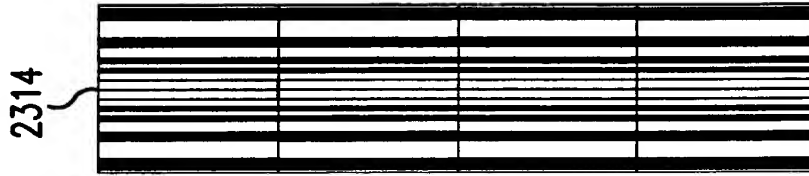
23/39



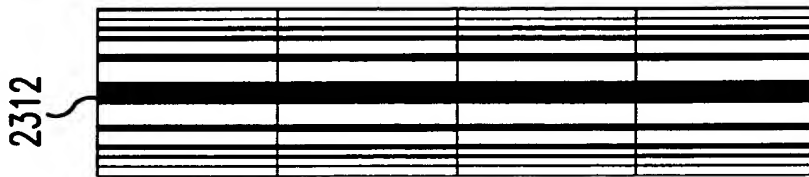
CIRCULAR ZONE  
 PLATE ARRAY  
 FIG. 23E



INTERLACED CHIRPED  
 HOLOGRAPHIC STRUCTURES  
 FIG. 23D



REVERSE CYLINDER  
 ZONE PLATE  
 FIG. 23C



CYLINDER ZONE  
 PLATE  
 FIG. 23B

FIG. 23E

24/39

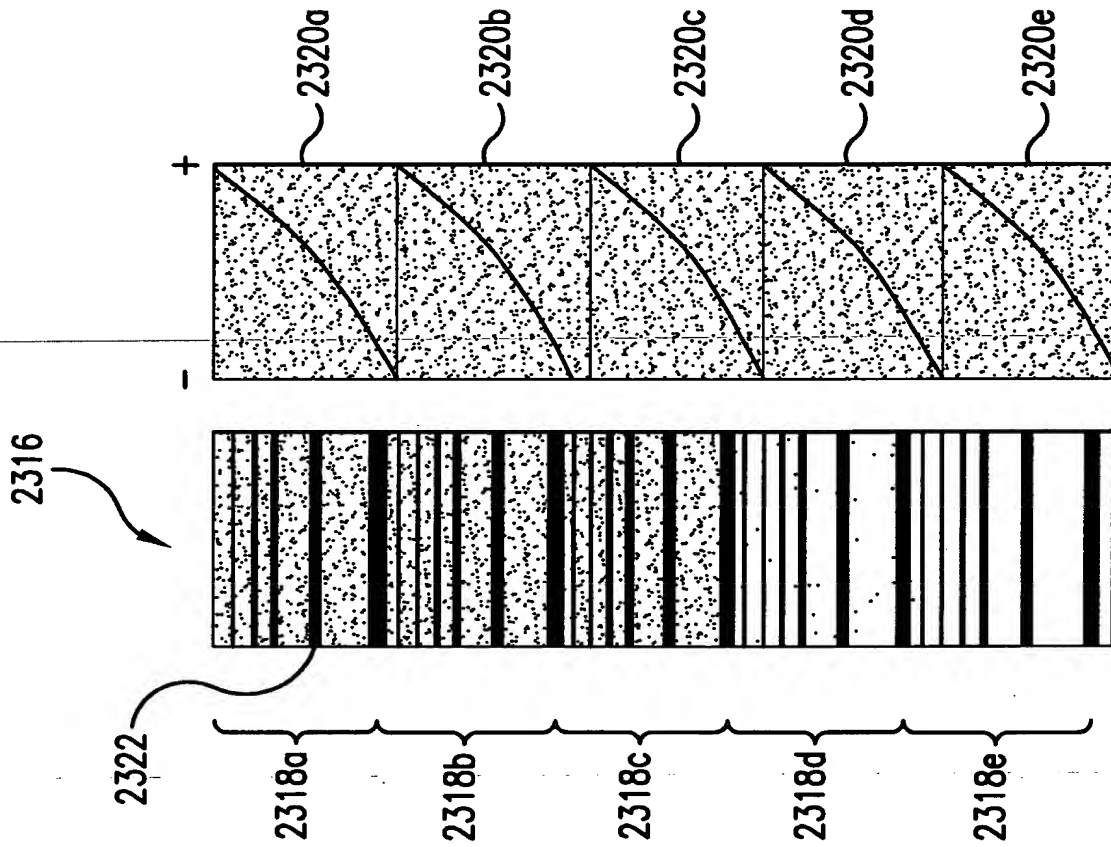


FIG. 23F

FIG. 23F 20040600



25/39

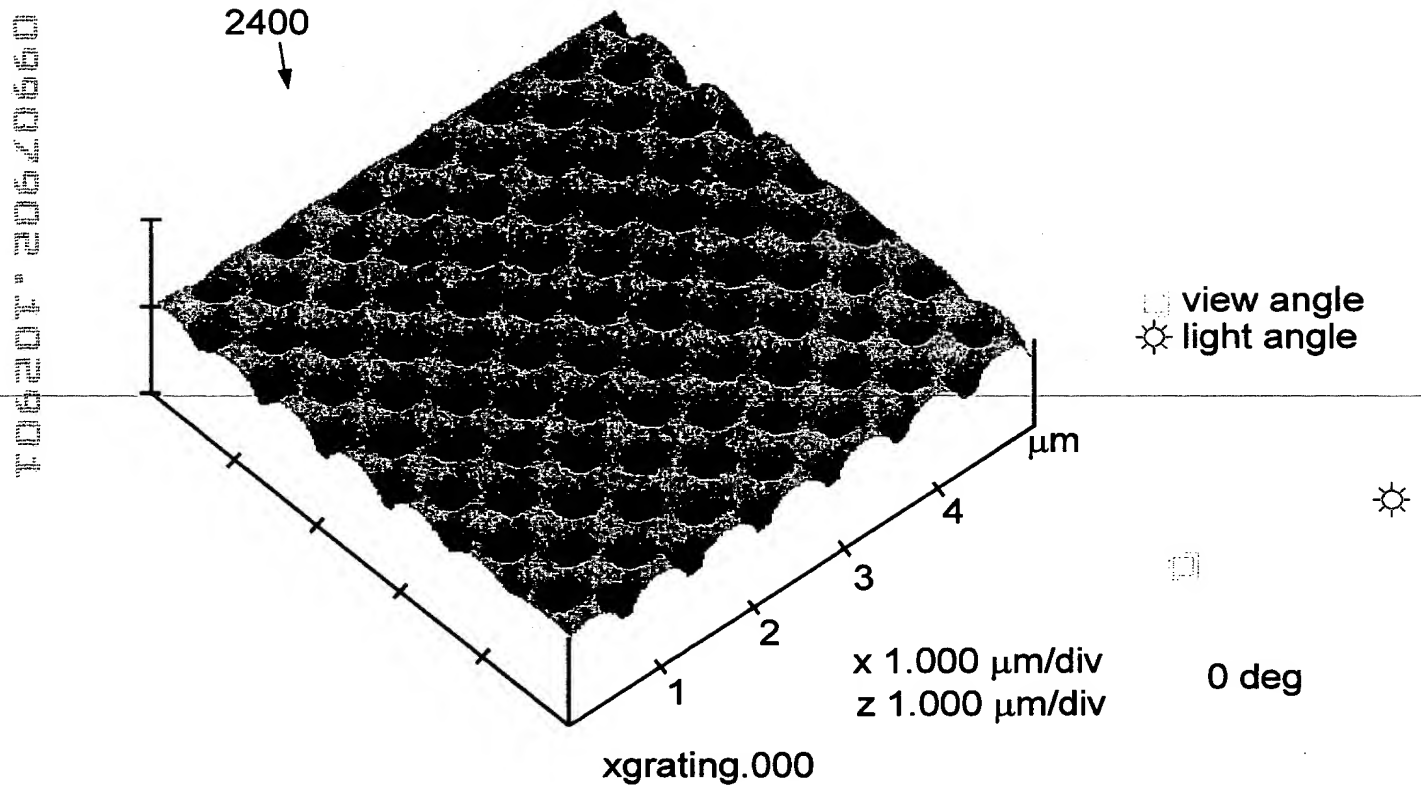


FIG.24

26/39

2500

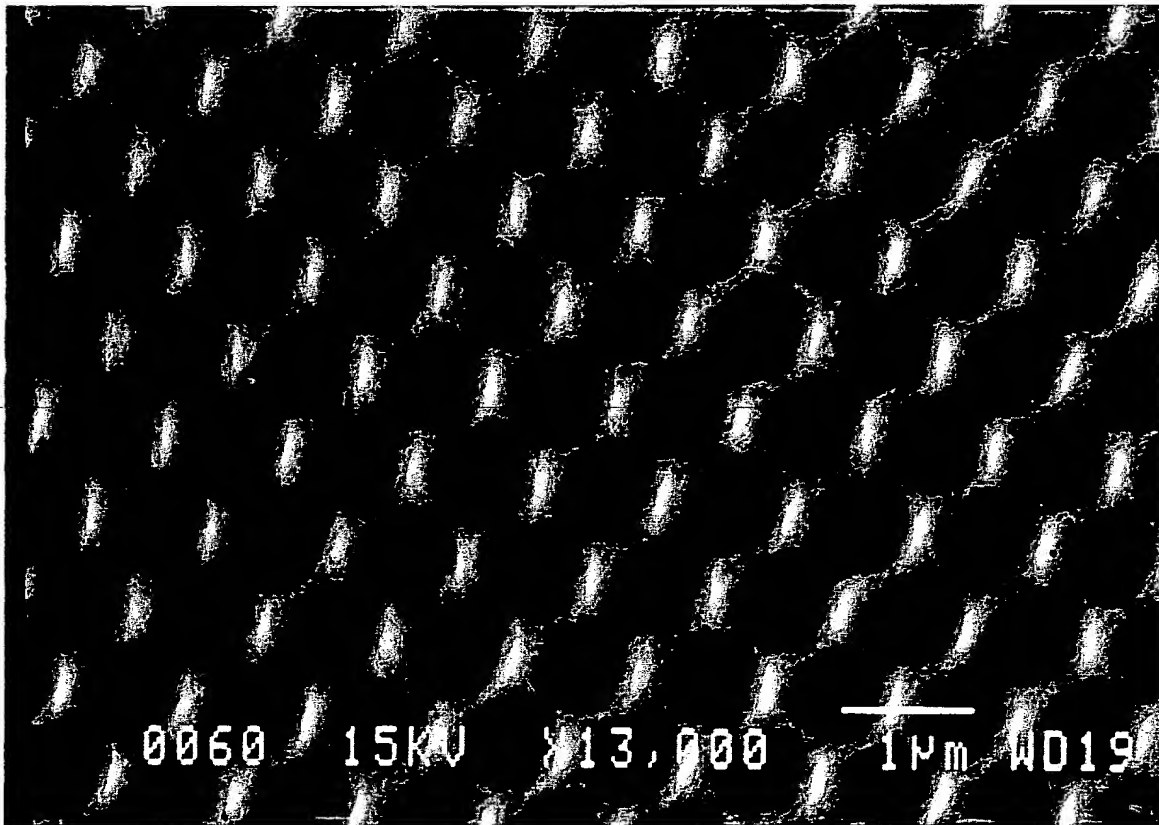


FIG. 25

27/39

FO620T-20670660

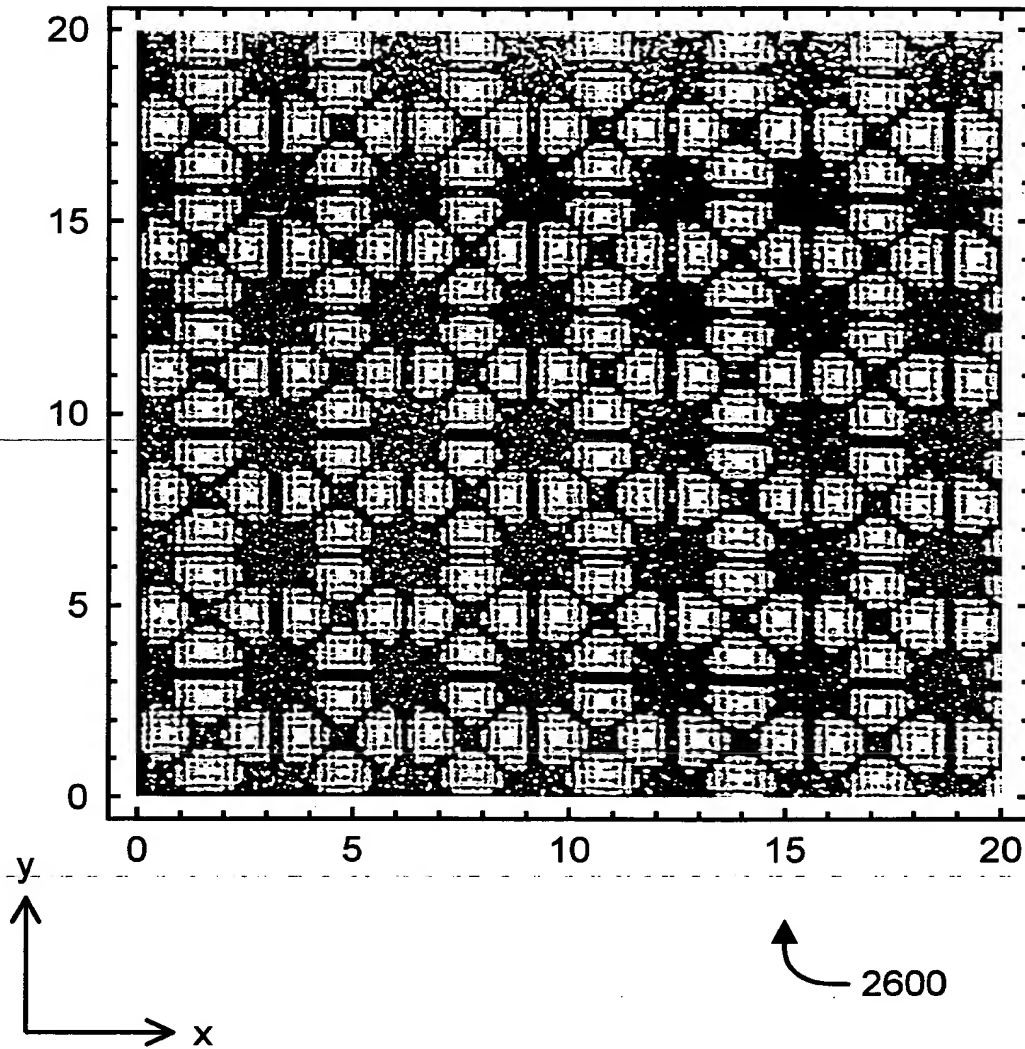


FIG.26

Appl. No. 09/907,902; Group Art Unit: 2621  
Dkt. No. 1875.0300001;  
Inventor(s): Matthew E. Hansen; Tel: 202/371-2600  
Title: System and Method for Characterizing Optical System  
Using Holographic Reticles

28/39

2700

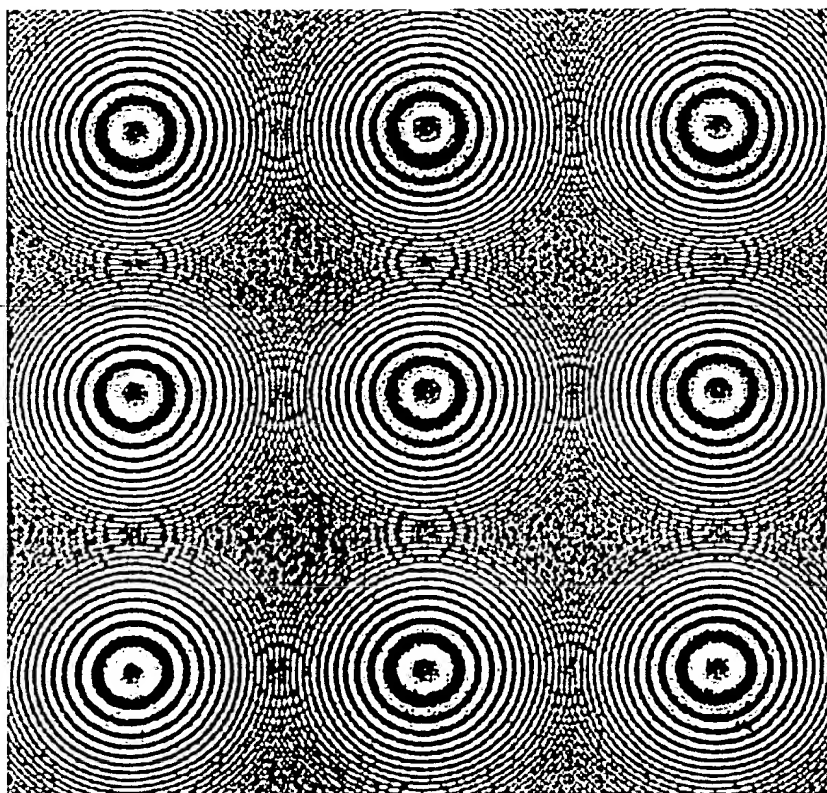


FIG. 27

09907902 2006/0660

29/39

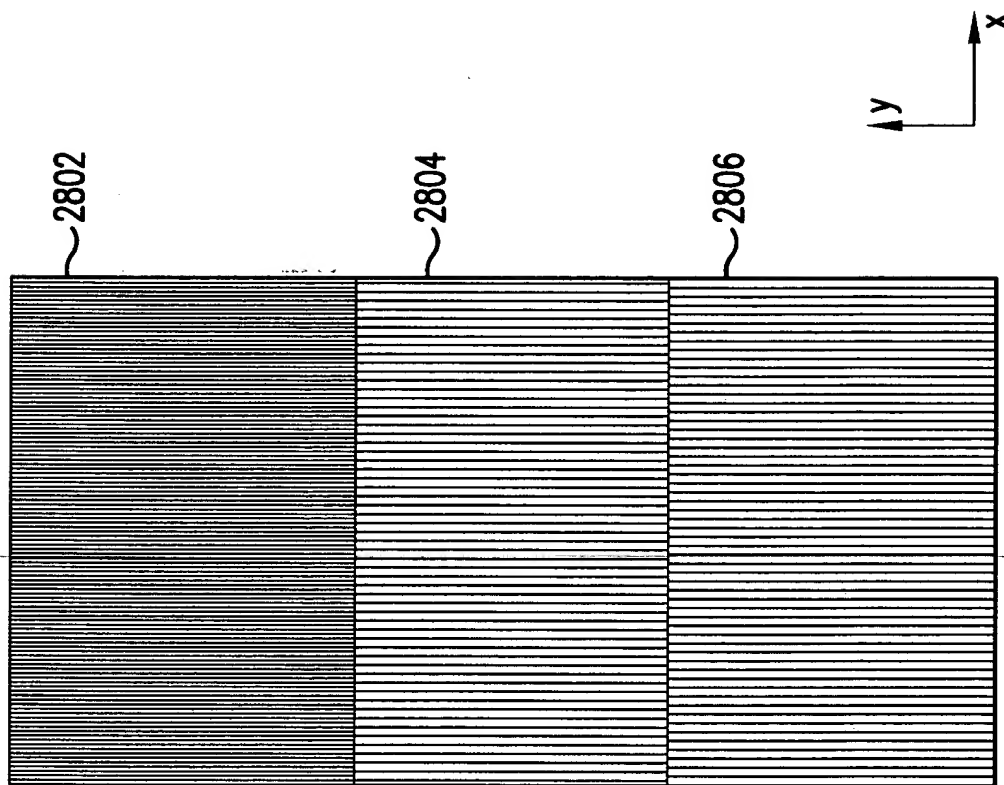


FIG.28

PITCH CHANGE

PHASE CHANGE

30/39

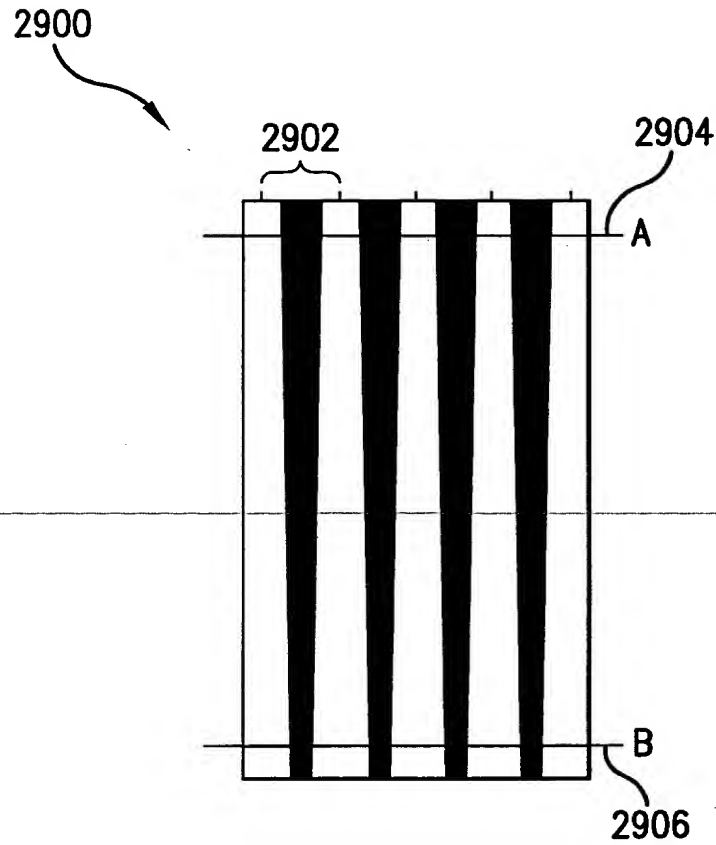


FIG. 29A

FIG. 29A

31/39

2908

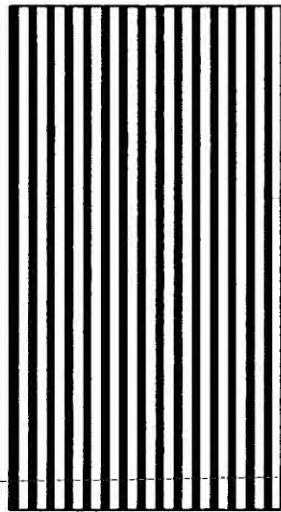
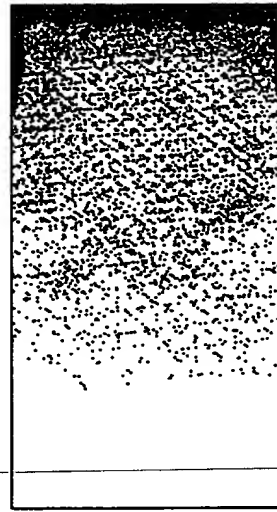


FIG. 29B

2910



2914

2912

FIG. 29C

FIG. 29B

32/39

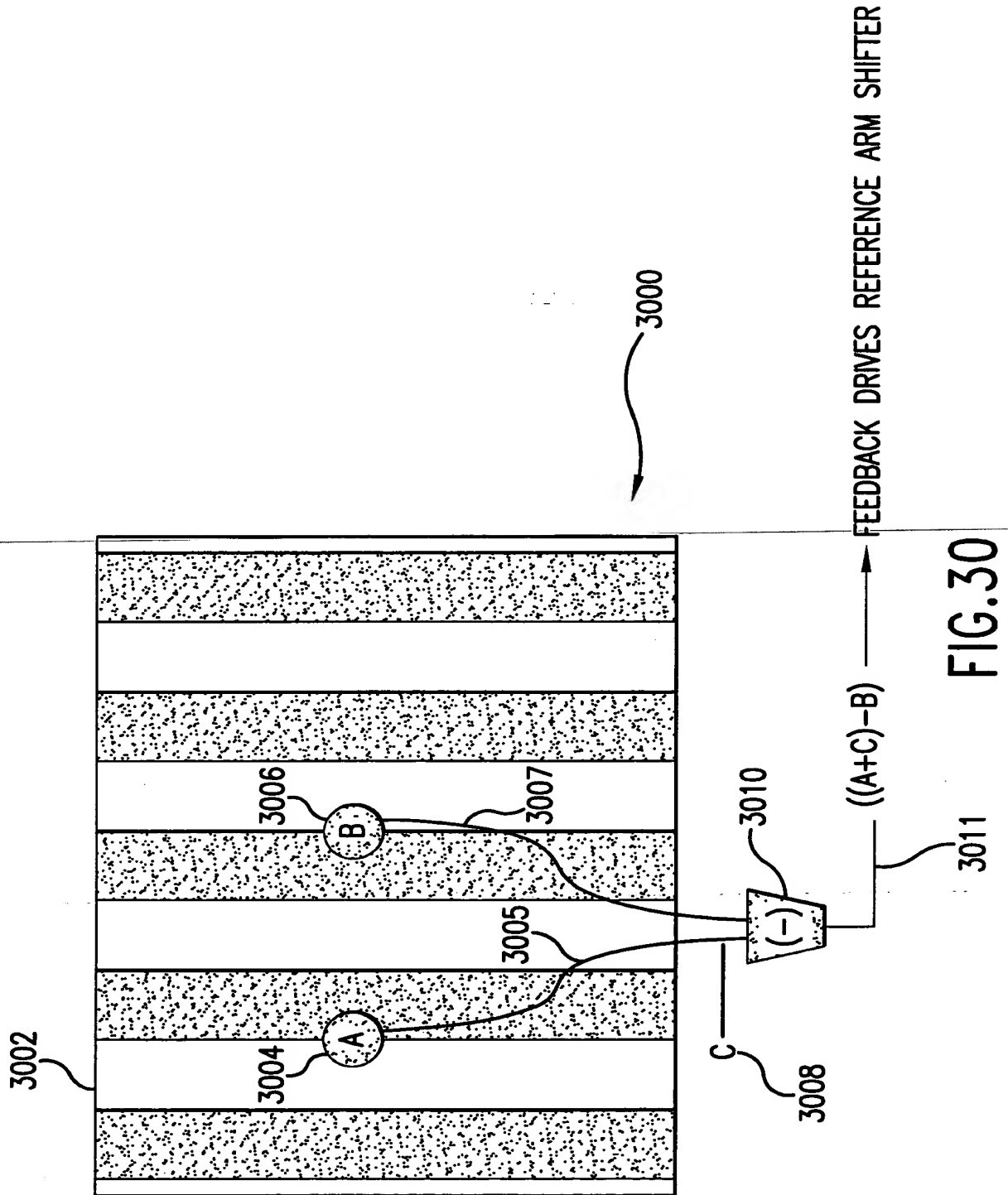


FIG.30

FOSSOT-20620660



33/39

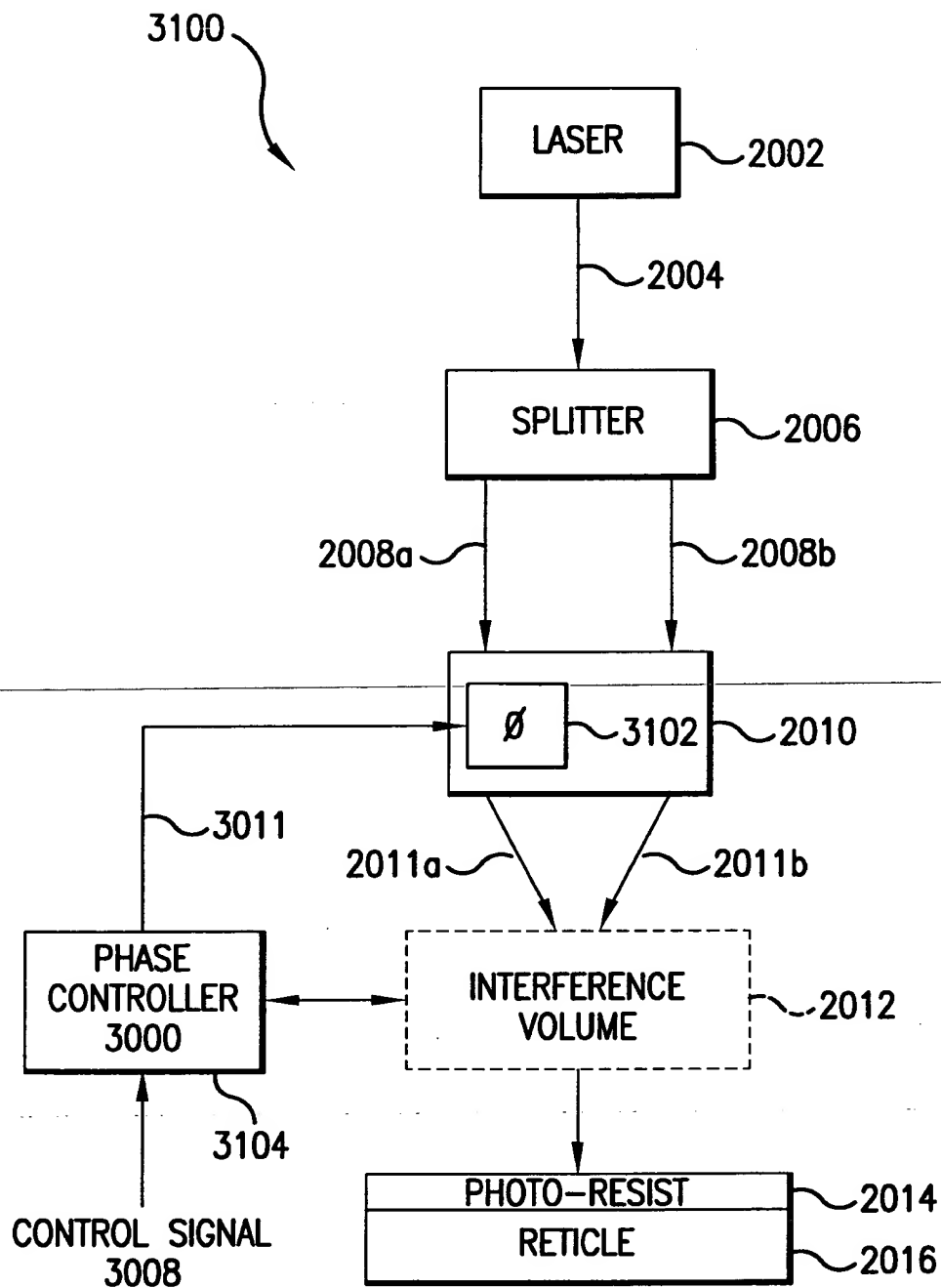


FIG.31

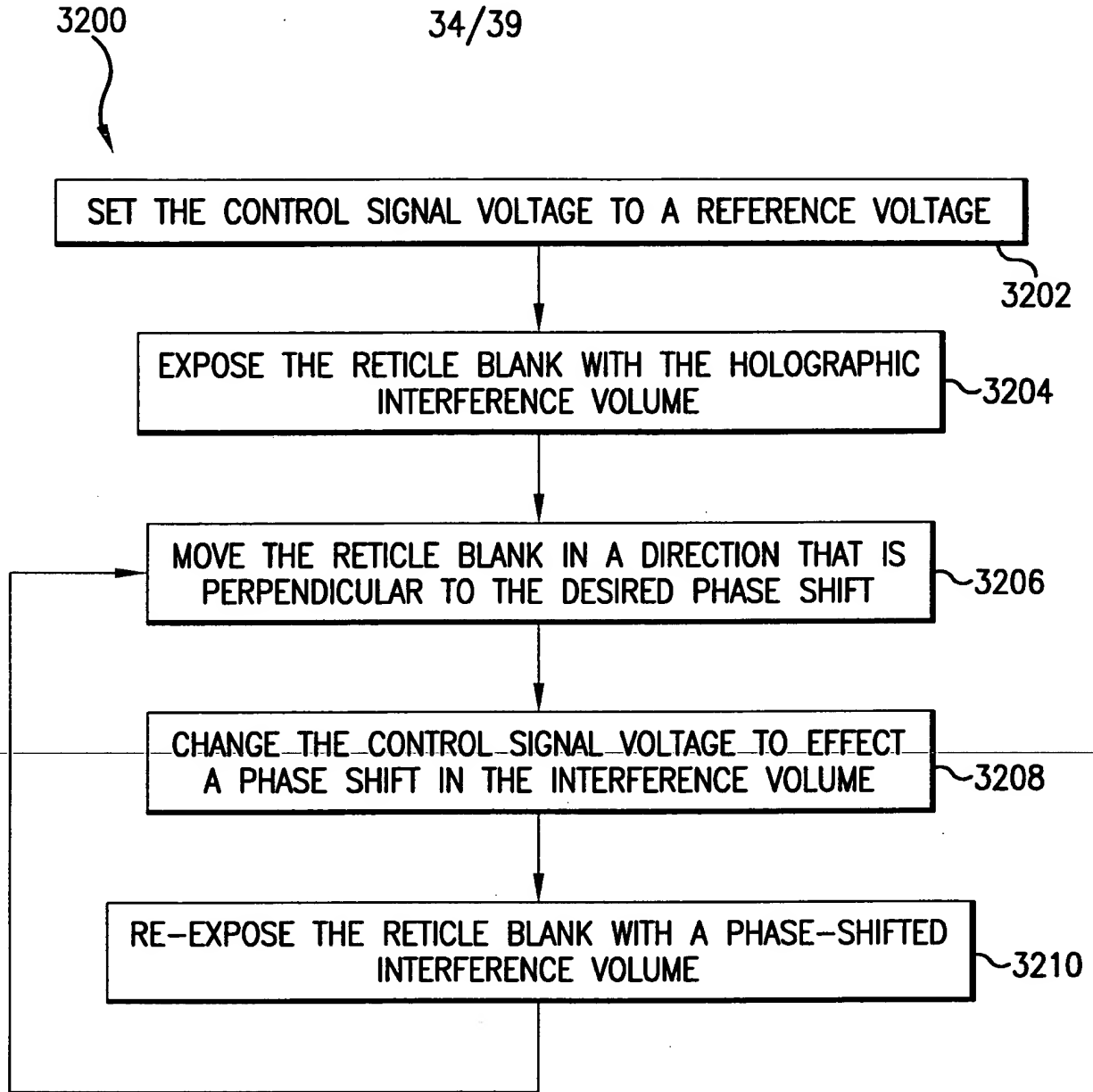


FIG.32

09907902-102901

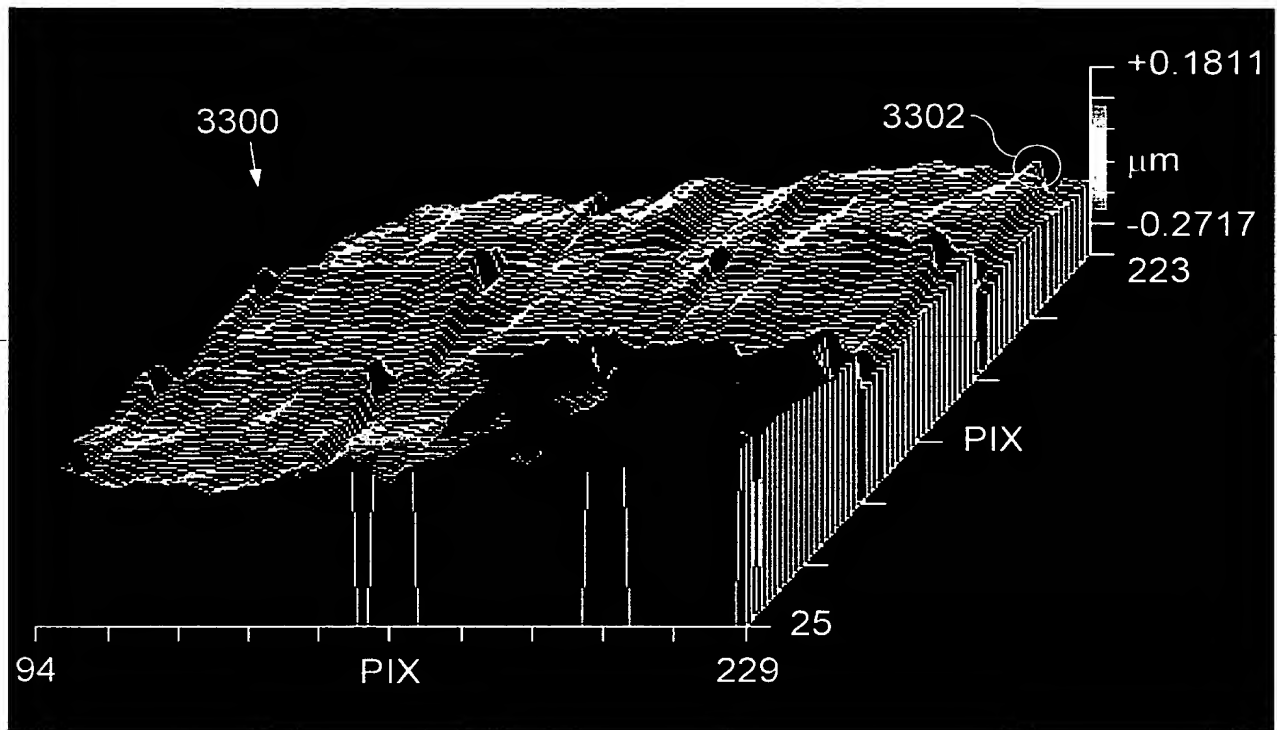


FIG.33

Appl. No. 09/907,902; Group Art Unit: 2621  
 Dkt. No. 1875.0300001;  
 Inventor(s): Matthew E. Hansen; Tel: 202/371-2600  
 Title: System and Method for Characterizing Optical System  
 Using Holographic Reticles

36/39

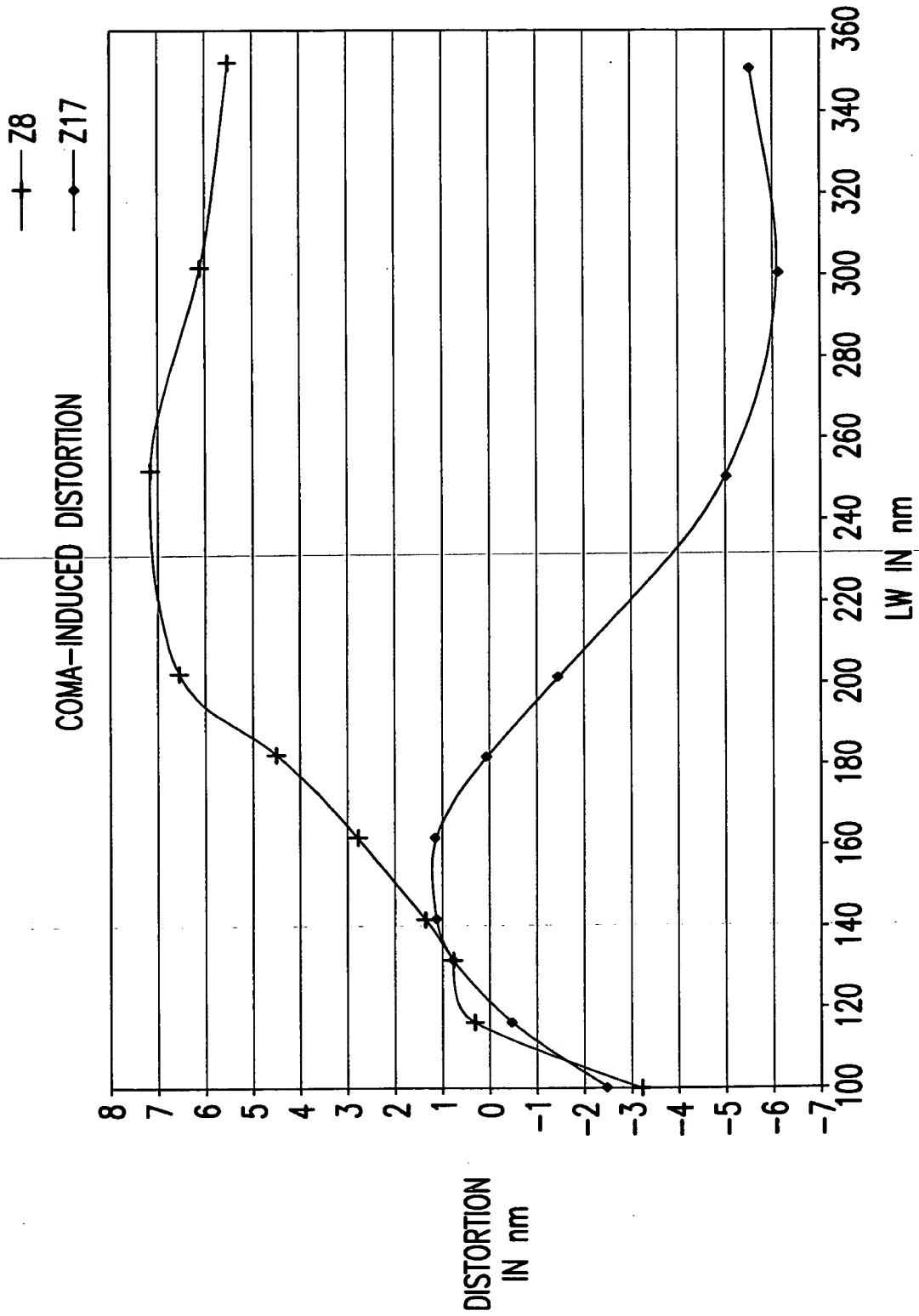


FIG.34

Appl. No. 09/907,902; Group Art Unit: 2621  
 Dkt. No. 1875,0300001;  
 Inventor(s): Matthew E. Hansen; Tel: 202/371-2600  
 Title: System and Method for Characterizing Optical System  
 Using Holographic Reticles

37/39

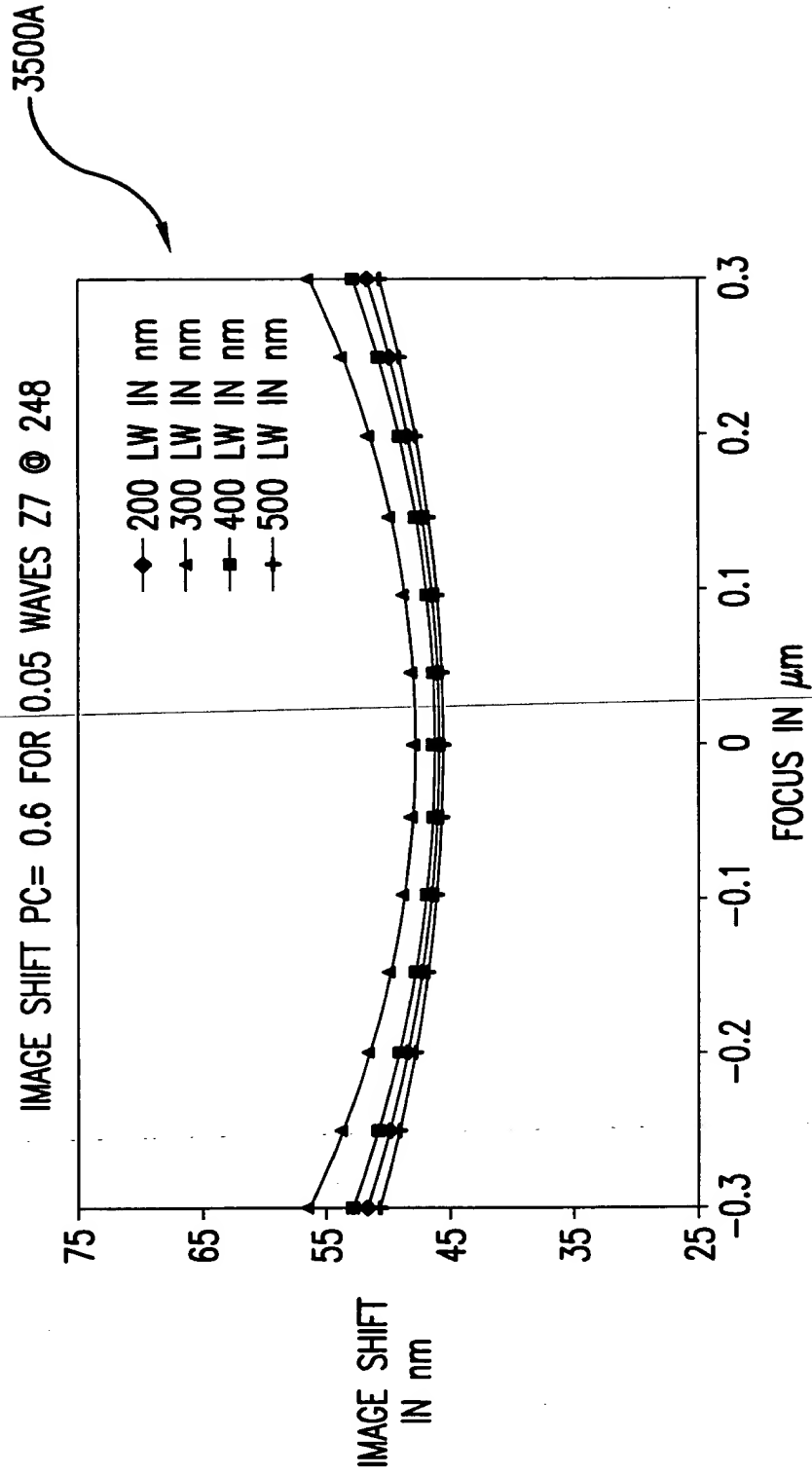


FIG. 35A

Appl. No. 09/907,902; Group Art Unit: 2621  
 Dkt. No. 1875.0300001;  
 Inventor(s): Matthew E. Hansen; Tel: 202/371-2600  
 Title: System and Method for Characterizing Optical System  
 Using Holographic Reticles

38/39

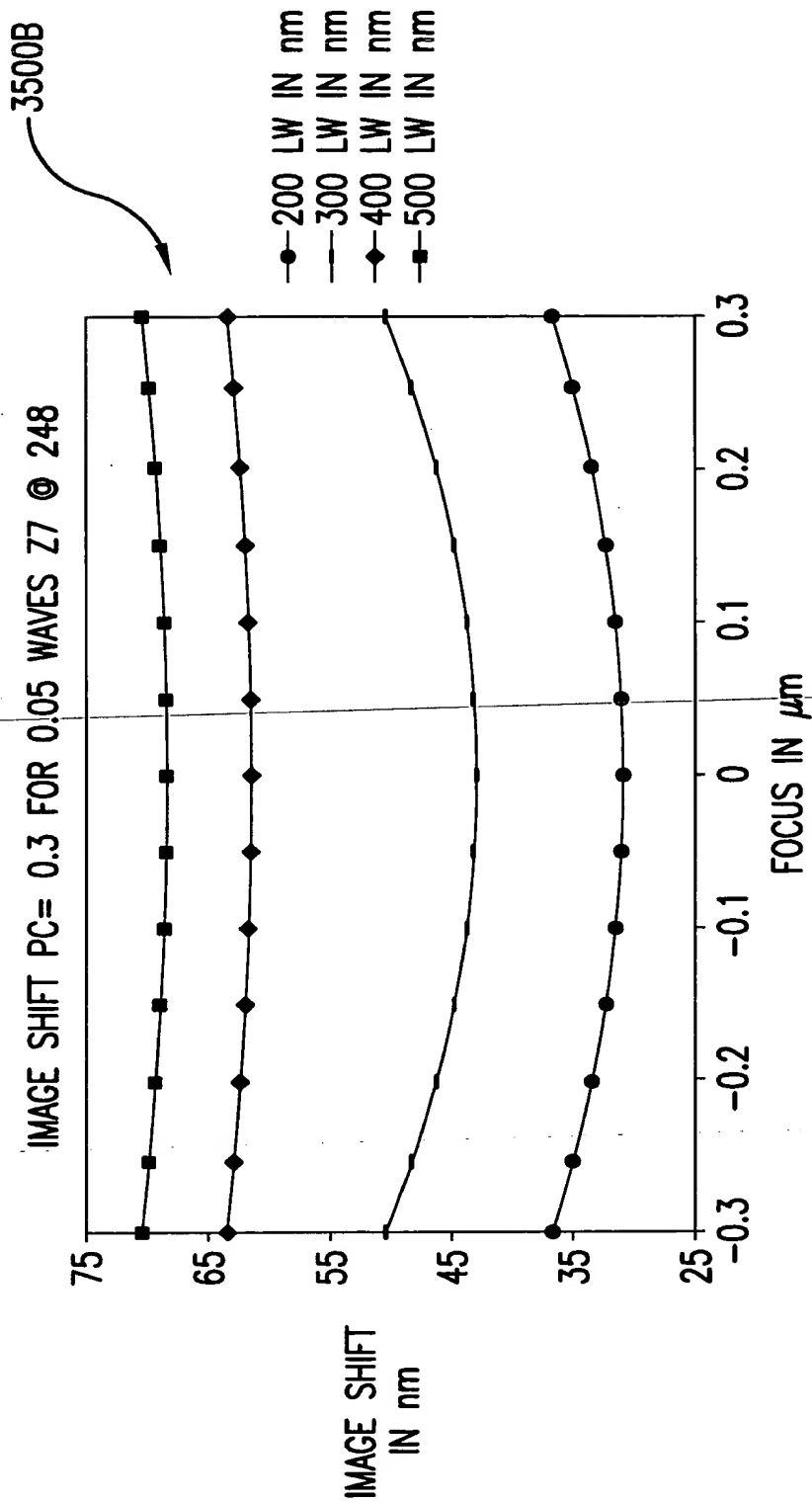


FIG. 35B

39/39

3600  


	DIFFRACTION ORDER			
LINEWIDTH	1ST	2ND	3RD	4TH
100 nm	a			
200 nm	b	a		
300 nm	c		a	
400 nm	d	b		a
600 nm	e	c		
800 nm		d	b	
900 nm			c	
1000 nm				b
1200 nm		e	d	c

FIG.36

09907902-102901